

Name and Address:

 ${\bf Laboratory\ name} \quad \ {\bf Rafael\ -\ Calibration\ Laboratories\ Ltd.}$ 

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As declared by the Organization, following is a list of the permanent sites and the phones numbers at which accredited activities are preformed.

• P Haifa

• *P1* **Leshem** +972-4-990-6529

**Definitions:** 

#### Main site:

A central site where the quality system is controlled for all sites where tests, calibrations or sampling are preformed.

#### Permanent site (Branch):

Permanent or temporary site existing longer than 6 months where at, or from which, the activities part of the accreditation schedule are preformed

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibra	ation –	Electri	ical Quantities - DC and	LF		כיול – גדלים חשמליים - זרם ישר ותדר נמוך			
1	A	P	DC Voltage, Measuring	מכשירי מדידת מתח בזרם ישר	±100 mV	1 μV/V	Manufacturer instructions	Standard cell	
2	A	P	Instruments		±1 V	1 μV/V	SOP 10700	Fluke 732A	
3	A	P			±1.018 V	2 μV/V		Fluke DMM 8508A Datron 4808	
4	A	P			±10 V	1 μV/V		Fluke 5730A	
5	A	P			±100 V	1.5 μV/V			
6	A	P			$\pm 1000~V$	1.5 μV/V			
7	A	P			Short	10 nV			
8	A	P			[0 mV to 200 mV]	1μV			
9	A	P			(200 mV to 2 V]	$4 \mu V/V$			
10	A	P			(2 V to 20 V]	2 μV/V			
11	A	P			(20 V to 200 V]	3 μV/V			
12	A	P			(200 V to 1100 V]	3 μV/V			
13	A	Т			Short	0.1 μV			
14	A	Т			[0 to 200 mV]	3.2 μV			
15	A	Т			(200 mV to 2 V]	15 μV/V			
16	A	Т			(2 V to 20 V]	10 μV/V			
17	A	Т			(20 V to 200 V]	13 μV/V			
18	A	Т			(200 V to 1100 V]	14 μV/V			

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests: Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Insti	rument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electri	ical Quantities - DC and	LF			ם ישר ותדר נמוך	ביול – גדלים חשמליים - זר
19	A	P	DC Voltage, Sources	מחוללי מתח בזרם ישר	$\pm 100~\text{mV}$	1 μV/V	Manufacturer instructions	Standard cell
20	A	P		Ì	±1 V	1 μV/V	SOP 10500	Fluke 732A
21	A	Р		,	±1.018 V	1 μV/V	SOP 10650	Fluke DMM 8508A
								Wavetek MTS 4950
22	A	P			±10 V	1 μV/V		
23	A	P			±100 V	$1 \mu V/V$		
24	A	P			±1000 V	1.9 μV/V		
25	A	P			[0 to 200 mV]	1μV		
26	A	P			(200 mV to 2 V]	2.6 μV/V		
27	A	P		ì	(2 V to 20 V]	2.0 μV/V		
28	A	P		ì	(0 V to 200 V]	3.0 μV/V		
29	A	P			(200 V to 1100 V]	2.5 μV/V		
30	A	Т			[0 to 50 mV]	1 μV		Fluke DMM 8508A
31	A	Т			(50 mV to 200 mV]	15 μV/V		
32	A	Т			(200 mV to 2 V]	10 μV/V		
33	A	Т			(2 V to 20 V]	8.5 μV/V		
34	A	Т			(20 V to 200 V]	14 μV/V		
35	A	Т			(200 V to 1100 V]	14 μV/V		

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	cal Quantities - DC and	LF		יול – גדלים חשמליים - זרם ישר ותדר נמוך		
36	A	P	DC Current, Measuring	זרם ישר, מכשירי מדידה	100 μΑ	7.5 μA/A	Manufacturer instructions	Standard resistors
37	A	P	Instruments		1 mA	6 μΑ/Α	SOP 10700	Fluke DMM 8508A
38	A	P			10 mA	6 μΑ/Α		Wavetek MTS 4950
								Datron Calibrator 4808
39	A	P			100 mA	6 μΑ/Α		
40	A	P			1 A	6 μΑ/Α		
41	A	P			10 A	30 μΑ/Α		Datron 4600
42	A	P			Open	0.1 nA		Transconductance amplifier
12					FO : 200 A1			Wavetek 9100
43	A	P			[0 to 200 µ A]	0.9 nA		Current Coils
44	A	P			$(200 \mu\text{A to 2 mA}]$	9 nA		
45	A	P			(2 mA to 20 mA]	90 nA		
46	A	P			(20 mA to 200 mA]	0.9 μΑ		
47	A	P			(200 mA to 2 A]	9 μΑ		
48	A	P			(2 A to 11 A]	30 μΑ/Α		
49	A	P			(11 A to 20 A]	770 μΑ/Α		
50	A	P			(20 A to 1000 A]	2 mA/A		
51	A	Т			Open	0.1 nA		Datron Calibrator 4808
52	A	Т			[ $0 \mu A$ to $20 \mu A$ ]	5 nA		
53	A	Т			$(20~\mu A~to~50~\mu A]$	10 nA		

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	cal Quantities - DC and	LF	· · · · · · · · · · · · · · · · · · ·		ם ישר ותדר נמוך	כיול – גדלים חשמליים - זו
54	A	Т			(50 μA to 200 μA]	175 μΑ/Α		
55	A	Т			(200 µA to 1 mA]	75 nA		
56	A	Т			(1 mA to 2 mA]	75 μA/A		
57	A	Т			(2 mA to 10 mA]	0.75 μΑ		
58	A	Т			(10 mA to 20 mA]	75 μA/A		
59	A	Т			(20 mA to 100 mA]	7.5 μΑ		
60	A	Т			(100 mA to 200 mA]	75 μA/A		
61	A	Т			(200 mA to 500 mA]	90 μΑ		
62	A	Т			(500 mA to 2 A]	175 μΑ/Α		
63	A	Т			(2 A to 5 A]	1.2 mA		
64	A	Т			(5 A to 10 A]	240 μΑ/Α		
65	A	Т			(10 A to 20 A]	1100 μΑ/Α		
66	A	Т			(20 A to 1000 A]	2 mA/A		
67	A	P	DC Current, Sources	זרם ישר, מקורות	100 μΑ	7 μΑ/Α	Manufacturer instructions	Standard resistors
68	A	P			1 mA	6 μΑ/Α	SOP 10560	Fluke DMM 8508A
69	A	P			10 mA	6 μΑ/Α	SOP 10562 SOP 10650	Wavetek MTS 4950 Datron 4808
70	A	P			100 mA	6 μΑ/Α		Datron 9100
71	A	P			1 A	6 μΑ/Α		Current coils

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	cal Quantities - DC and LF	· · · · · · · · · · · · · · · · · · ·		רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
72	A	P		10 A	30 μΑ/Α		Current clamp
73	A	P		[0 μA to 200 μA]	1 nA		
74	A	P		(200 µA to 2 mA]	9 μΑ/Α		
75	A	P		(2 mA to 20 mA]	9 μΑ/Α		
76	A	P		(20 mA to 200 mA]	9 μΑ/Α		
77	A	P		(200 mA to 2 A]	9 μΑ/Α		
78	A	P		(2 A to 11 A]	30 μΑ/Α		
79	A	P		(11 A to 1000 A]	2 mA/A	Manufacturer instructions	Fluke DMM 8508A
80	A	T		[0 μA to 10 μA]	6 nA		Wavetek 4953
81	A	T		(10 μA to 100 μA]	17 nA		Current clamp Kyoritsu 2003
82	A	T		(100 μA to 200 μA]	30 nA		
83	A	T		(200 µA to 1 mA]	160 nA		
84	A	T		(1 mA to 2 mA]	275 nA		
85	A	T		(2 mA to 10 mA]	1.6 μΑ		
86	A	T		(10 mA to 20 mA]	2.75 μΑ		
87	A	T		(20 mA to 100 mA]	16 μΑ		
88	A	T		(100 mA to 200 mA]	27.5 μΑ		
89	A	T		(200 mA to 1 A]	286 μΑ		

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#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Inst	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	ical Quantities - DC and	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - זו
90	A	T			(1 A to 2 A]	286 μΑ/Α		
91	A	Т			(2 A to 11 A]	125 μΑ/Α		
92	A	T			(11 A to 1000 A]	17 mA/A		
93	A	P	DC Resistance, Resistors	התנגדות זרם ישר, נגדים	0.001 Ω	75 μΩ/Ω	Manufacturer instructions	Standard resistors
94	A	P			0.01 Ω	20 μΩ/Ω	SOP 10800	Datron 4808 Wavetek 9100
95	A	P			0.1 Ω	10 μΩ/Ω		Fluke 8508A
96	A	P			1 Ω	1 μΩ/Ω		Wavetek 4950
97	A	P			$10\Omega$	2 μΩ/Ω		
98	A	P			25 Ω	4 μΩ/Ω		
99	A	P			50 Ω	4 μΩ/Ω		
100	A	P			$100~\Omega$	3 μΩ/Ω		
101	A	P			$200\Omega$	4 μΩ/Ω		
102	A	P			$400~\Omega$	8 μΩ/Ω		
103	A	P			1 kΩ	5 μΩ/Ω		
104	A	P			$10~\mathrm{k}\Omega$	10 μΩ/Ω		
105	A	P			$100~\mathrm{k}\Omega$	10 μΩ/Ω		
106	A	P			$1~\mathrm{M}\Omega$	10 μΩ/Ω		
107	A	P			$10~\mathrm{M}\Omega$	20 μΩ/Ω		

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח מה למספר הנספח ומספרה ומספרה ומספרה הנספח ומספרה ו

# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument	auge Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibro	ation –	Electric	cal Quantities - DC and LF			ם ישר ותדר נמוך	כיול – גדלים חשמליים - זו
108	A	P		100 ΜΩ	50 μΩ/Ω		
109	A	P		1 GΩ	0.1 %		Keithley 5155
110	A	P		10 GΩ	2 mΩ/Ω		Keithley 5155
111	A	P		100 GΩ	1 mΩ/Ω		Keithley 5155
112	A	P		1000 GΩ	1 mΩ/Ω		Keithley 5155
113	A	P		(0 to 1Ω]	23 μΩ	Manufacturer instructions SOP 10650	Fluke 8508A
114	A	P		$(1~\Omega~{ m to}~20~\Omega]$	5 μΩ/Ω	SOP 10030	
115	A	P		$(20~\Omega~{ m to}~200~\Omega]$	5 μΩ/Ω		
116	A	P		$(200~\Omega~{ m to}~2~{ m k}\Omega]$	8 μΩ/Ω		
117	A	P		$(2 \text{ k}\Omega \text{ to } 20 \text{ k}\Omega]$	10 μΩ/Ω		
118	A	P		(20 k $\Omega$ to 200 k $\Omega$ ]	10 μΩ/Ω		
119	A	P		(200 k $\Omega$ to 2 M $\Omega$ ]	10 μΩ/Ω		
120	A	P		$(2~M\Omega$ to $20~M\Omega]$	$40~\mu\Omega/\Omega$		
121	A	P		(20 M $\Omega$ to 100 M $\Omega$ ]	$220~\mu\Omega/\Omega$		
122	A	T		(0 to 1 Ω]	45 μΩ		
123	A	T		(1 Ω to 5 Ω]	43 μΩ/Ω		
124	A	Т		(5 $\Omega$ to 20 $\Omega$ ]	25 μΩ/Ω		

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instr	rument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	ical Quantities - DC and I	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
125	A	T			$(20~\Omega~to~200~\Omega]$	18 μΩ/Ω		
126	A	T			$(200~\Omega~to~2~k\Omega]$	$18~\mu\Omega/\Omega$		
127	A	T			(2 k $\Omega$ to 20 k $\Omega$ ]	$18~\mu\Omega/\Omega$		
128	A	T			(20 k $\Omega$ to 200 k $\Omega$ ]	19 μΩ/Ω		
129	A	T			(200 k $\Omega$ to 2 M $\Omega$ ]	31 μΩ/Ω		
130	A	T			$(2~M\Omega~to~20~M\Omega]$	95 μΩ/Ω		
131	A	T			(20 $M\Omega$ to 100 $M\Omega]$	950 μΩ/Ω		
132	A	P	DC Resistance, Measuring	התנגדות זרם ישר, מכשירי מדידה	0.001 Ω	90 μΩ/Ω	Manufacturer Instructions	Standard resistors
133	A	P	Instruments	111712	0.01 Ω	30 μΩ/Ω	SOP 10700	Wavetek 9100
134	A	P			0.1 Ω	10 μΩ/Ω		Fluke 8508A G.R. Decade resistors
135	A	P			1 Ω	$0.5~\mu\Omega/\Omega$		Wavetek 4950
136	A	P			$10\Omega$	2 μΩ/Ω		
137	A	P			25 Ω	3 μΩ/Ω		
138	A	P			50 Ω	3 μΩ/Ω		
139	A	P			$100\Omega$	3 μΩ/Ω		
140	A	P			$200\Omega$	5 μΩ/Ω		
141	A	P			1 kΩ	5 μΩ/ <b>Ω</b>		
142	A	P			10 kΩ	10 μΩ/Ω		

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electri	cal Quantities - DC and LF			ם ישר ותדר נמוך	כיול – גדלים חשמליים - זו
143	A	P		100 kΩ	10 μΩ/Ω		
144	A	P		$1~\mathrm{M}\Omega$	$10$ μ $\Omega/\Omega$		
145	A	P		$10~\mathrm{M}\Omega$	$30~\mu\Omega/\Omega$		
146	A	P		$100~\mathrm{M}\Omega$	$50~\mu\Omega/\Omega$		
147	A	P		1 GΩ	0.1 %		Keithley 5155
148	A	P		$10~\mathrm{G}\Omega$	0.2 %		Keithley 5155
149	A	P		$100~\mathrm{G}\Omega$	0.1 %		Keithley 5155
150	A	P		$1000~\mathrm{G}\Omega$	0.1 %		Keithley 5155
151	A	P		$(0 \text{ to } 5 \Omega]$	120 μΩ		
152	A	P		$(5 \Omega \text{ to } 20 \Omega]$	22 μΩ/Ω		
153	A	P		$(20~\Omega~to~200~\Omega]$	17 μΩ/Ω		
154	A	P		(200 $\Omega$ to 2 $k\Omega$ ]	15 μΩ/Ω		
155	A	P		$(2 \text{ k}\Omega \text{ to } 20 \text{ k}\Omega]$	23 μΩ/Ω		
156	A	P		(20 k $\Omega$ to 200 k $\Omega$ ]	15 μ $\Omega$ / $\Omega$		
157	A	P		(200 k $\Omega$ to 2 M $\Omega$ ]	$37~\mu\Omega/\Omega$		
158	A	P		$(2 \text{ M}\Omega \text{ to } 20 \text{ M}\Omega]$	95 μΩ/Ω		
159	A	P		$(20~{\rm M}\Omega~{\rm to}100~{\rm M}\Omega]$	250 μΩ/Ω		
160	A	T		(0 to 0.1 $\Omega$ ]	10 μΩ	Manufacturer instructions	Wavetek 9100

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#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electri	ical Quantities - DC and LF			רם ישר ותדר נמוך	ביול – גדלים חשמליים - זו
161	A	T		(0.1 to 5 Ω]	$140~\mu\Omega$		G.R. Decade resistors
162	A	Т		$(5 \Omega \text{ to } 20 \Omega]$	$28\mu\Omega/\Omega$		
163	A	Т		$(20~\Omega$ to $200~\Omega]$	$18~\mu\Omega/\Omega$		
164	A	Т		$(200~\Omega~\text{to}~2~\text{k}\Omega]$	$18~\mu\Omega/\Omega$		
165	A	Т		$(2 \text{ k}\Omega \text{ to } 20 \text{ k}\Omega]$	$23~\mu\Omega/\Omega$		
166	A	Т		$(20~\text{k}\Omega~\text{to}~200~\text{k}\Omega]$	$19$ μ $\Omega/\Omega$		
167	A	Т		$(200~\text{k}\Omega~\text{to}~2~\text{M}\Omega]$	$37~\mu\Omega/\Omega$		
168	A	Т		$(2~{\rm M}\Omega~{\rm to}~20~{\rm M}\Omega]$	95 μ $\Omega/\Omega$		
169	A	Т		$(20~{\rm M}\Omega~{\rm to}~100~{\rm M}\Omega]$	$950~\mu\Omega/\Omega$		
			AC Voltage, Sources מתח חילופין, מחוללים	100 mV		Manufacturer instructions	Datron 4920
170	A	P		1 kHz	$41~\mu V/V$	SOP 10550	Datron 4922
171	A	P		30 kHz	$77~\mu V/V$		Wavetek MTS 4950
172	A	P		60 kHz	$97~\mu V/V$		
173	A	P		100 kHz	$97~\mu V/V$		
				300 mV			
174	A	P		40 Hz	$33  \mu V/V$		
175	A	P		1 kHz	$34\;\mu V/V$		
176	A	P		30 kHz	$45~\mu\text{V/V}$		

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#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibre	ation –	Electri	cal Quantities - DC and	<b>LF</b>			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
177	A	P			50 kHz	73 μV/V		
178	A	P			100 kHz	$74\muV/V$		
179	A	P			200 kHz	$140\;\mu\text{V/V}$		
180	A	P			500 kHz	$280\;\mu V/V$		
181	A	P			700 kHz	$720\;\mu\text{V/V}$		
182	A	P			1 MHz	$720~\mu\text{V/V}$		
					1 V			
183	A	P			10 Hz	$130 \ \mu V/V$		
184	A	P			40 Hz	$29 \; \mu V/V$		
185	A	P			1 kHz	$29\mu\text{V/V}$		
186	A	P			30 kHz	$30\mu V/V$		
187	A	P			50 kHz	$66\mu V/V$		
188	A	P			60 kHz	$67~\mu V/V$		
189	A	P			100 kHz	$68\mu V/V$		
190	A	P			200 kHz	$75~\mu V/V$		
191	A	P			500 kHz	$280~\mu V/V$		
192	A	P			700 kHz	720 µV/V		
193	A	P			1 MHz	$720~\mu\text{V/V}$		
194	A	P			50 MHz	20 mV/V		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests: Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.

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The certificate attached is an integral part of the schedule and is numbered identically המעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

#### Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	cal Quantities - DC and LF		יול – גדלים חשמליים - זרם ישר ותדר נמוך		
				3 V			
195	A	P		10 Hz	130 μV/V		
196	A	P		40 Hz	31 μV/V		
197	A	P		1 kHz	29 μV/V		
198	A	P		30 kHz	30 μV/V		
199	A	P		50 kHz	66 μV/V		
200	A	P		100 kHz	66 µV/V		
201	A	P		200 kHz	74 μV/V		
202	A	P		500 kHz	270 μV/V		
203	A	P		700 kHz	710 μV/V		
204	A	P		1 MHz	710 µV/V		
205	A	P		5 MHz	20 mV/V		
206	A	P		10 MHz	20 mV/V		
207	A	P		20 MHz	20 mV/V		
208	A	P		30 MHz			
200	11	-		5 V			
209	A	P		1 kHz	28 μV/V		
				10 V			
210	A	P		10 Hz	41 μV/V		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Inst	rument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	ical Quantities - DC and	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
211	A	P			40 Hz	$29\mu\text{V/V}$		
212	A	P			1 kHz	$28\mu\text{V/V}$		
213	A	P			30 kHz	$28\mu\text{V/V}$		
214	A	P			50 kHz	$66\mu V/V$		
215	A	P			60 kHz	$66\mu\text{V/V}$		
216	A	P			100 kHz	$66\mu V/V$		
217	A	P			200 kHz	$73 \mu V/V$		
218	A	P			500 kHz	$270~\mu\text{V/V}$		
219	A	P			700 kHz	$710~\mu\text{V/V}$		
220	A	P			1 MHz	$710~\mu\text{V/V}$		
					20 V			
221	A	P			500 kHz	$270~\mu\text{V/V}$		
222	A	P			700 kHz	$710~\mu\text{V/V}$		
223	A	P			1 MHz	$710~\mu\text{V/V}$		
					30 V			
224	A	P			10 Hz	$130~\mu V/V$		
225	A	P			40 Hz	$37 \muV/V$		
226	A	P			1 kHz	29 μV/V		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Inst	rument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	cal Quantities - DC and	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
227	A	P			30 kHz	$29 \; \mu V/V$		
228	A	P			50 kHz	$66\mu V/V$		
229	A	P			100 kHz	$71~\mu\text{V/V}$		
230	A	P			200 kHz	$89~\mu\text{V/V}$		
					100 V			
231	A	P			10 Hz	$43\;\mu\text{V/V}$		
232	A	P			40 Hz	$40~\mu\text{V/V}$		
233	A	P			1 kHz	$28\mu\text{V/V}$		
234	A	P			30 kHz	$28\mu\text{V/V}$		
235	A	P			50 kHz	$66 \muV/V$		
236	A	P			60 kHz	$66 \muV/V$		
237	A	P			100 kHz	$66\mu V/V$		
					300 V			
238	A	P			45 Hz	$44~\mu\text{V/V}$		
239	A	P			1 kHz	$43~\mu\text{V/V}$		
240	A	P			5 kHz	$45~\mu\text{V/V}$		
241	A	P			10 kHz	$43\mu\text{V/V}$		
242	A	P			15 kHz	$43\muV/V$		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically המעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המשרח ומספרה המשחדה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המשחדה המצורפת למספר הנספח המשחדה המצורפת למספר המשחדה המצורפת למספר הנספח ומספרה זהה למספר הנספח המשחדה במשחדה המצורפת למספר המשחדה במשחדה המצורפת למספר המשחדה המצורפת למספר המשחדה המשחדה המצורפת למספר המשחדה המשחדה המשחדה במשחדה המצורפת למספר המשחדה המצורפת למספר המשחדה המשחדה המשחדה המשחדה המשחדה המשחדה המצורפת למספר המשחדה המצורפת למספר המשחדה המשחדה

#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibre	ation –	Electri	cal Quantities - DC and LF		רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז	
243	A	P		20 kHz	$43~\mu\text{V/V}$		
244	A	P		33 kHz	$100~\mu\text{V/V}$		
245	A	P		50 kHz	$120~\mu V/V$		
246	A	P		100 kHz	$160~\mu\text{V/V}$		
				500 V			
247	A	P		100 kHz	$160~\mu\text{V/V}$		
				700 V			
248	A	P		50 kHz	$160~\mu\text{V/V}$		
				1000 V			
249	A	P		45 Hz	$45~\mu\text{V/V}$		
250	A	P		1 kHz	$45~\mu\text{V/V}$		
251	A	P		5 kHz	$45~\mu\text{V/V}$		
252	A	P		10 kHz	$48\mu V/V$		
253	A	P		15 kHz	$48\mu V/V$		
254	A	P		20 kHz	$48~\mu\text{V/V}$		
255	A	P		30 kHz	$110~\mu\text{V/V}$		
256	A	P		33 kHz	110 μV/V		
				[0.9 mV to 3 mV]			Datron 4920
257	A	P		[40 Hz to 200 kHz]	$490~\mu\text{V/V}$		Datron 4922

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electri	cal Quantities - DC and LF			חשמליים - זרם ישר ותדר נמוך	
258	A	P		(200 kHz to 500 kHz]	1400 μV/V		
259	A	P		(500 kHz to 1 MHz]	3.3 mV/V		
				(3 mV to 9 mV]			
260	A	P		[40 Hz to 200 kHz]	$350~\mu\text{V/V}$		
261	A	P		(200 kHz to 500 KHz]	1.1 mV/V		
262	A	P		(500 kHz to 1 MHz]	2.6 mV/V		
				(9 mV to 30 mV]			
263	A	P		[40 Hz to 200 kHz]	220 μV/V		
264	A	P		(200 kHz to 500 KHz]	620 μV/V		
265	A	P		(500 kHz to 1 MHz]	1.6 mV/V		
				(30 mV to 350 mV]			
266	A	P		[40 Hz to 200 kHz]	$150~\mu\text{V/V}$		
267	A	P		(200 kHz to 500 kHz]	$340~\mu\text{V/V}$		
268	A	P		(500 kHz to 1 MHz]	$860~\mu V/V$		
				(350 mV to 35 V]			
269	A	P		[40 Hz to 200 kHz]	$110~\mu\text{V/V}$		
270	A	P		(200 kHz to 500 kHz]	$350~\mu\text{V/V}$		
271	A	P		(500 kHz to 1 MHz]	860 μV/V		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibra	ation –	Electri	ical Quantities - DC and LF		כיול – גדלים חשמליים - זרם ישר ותדר נמוך			
				[1 V to 3.5 V]				
272	A	P		[1 MHz to 30 MHz]	20 mV/V			
				(35 V to 120 V]				
273	A	P		[10 Hz to 100 kHz]	85 μV/V			
				(20 V to 500 V]				
274	A	P		[45 Hz to 100 kHz]	$180~\mu\text{V/V}$			
				(500 V to 700 V]				
275	A	P		[45 Hz to 50 kHz]	$180~\mu\text{V/V}$			
				(700 V to 1000 V]				
276	A	P		[45 Hz to 33 kHz]	130 μV/V			
			AC Voltage. Measuring מתח חילופין, מכשירי מדידה	100 mV		Manufacturer instructions	Datron 4920	
277	A	P	Instruments	1 kHz	$41~\mu V/V$	SOP 10700	Datron 4922	
278	A	P		30 kHz	77 μV/V		Datron 4808	
279	A	P		60 kHz	97 μV/V			
280	A	P		100 kHz	97 μV/V			
				300 mV				
281	A	P		40 Hz	$34 \mu\text{V/V}$			
282	A	P		1 kHz	$35\mu V/V$			

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electri	cal Quantities - DC and LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
283	A	P		30 kHz	$45~\mu\text{V/V}$		
284	A	P		50 kHz	$73~\mu\text{V/V}$		
285	A	P		100 kHz	$74\mu\text{V/V}$		
286	A	P		200 kHz	$135 \mu\text{V/V}$		
287	A	P		500 kHz	$280~\mu\text{V/V}$		
288	A	P		700 kHz	720 μV/V		
289	A	P		1MHz	$720~\mu\text{V/V}$		
				1 V			
290	A	P		10 Hz	$130  \mu V/V$		
291	A	P		40 Hz	$30\mu V/V$		
292	A	P		1kHz	$29 \; \mu V/V$		
293	A	P		30 kHz	$31  \mu V/V$		
294	A	P		50 kHz	$67~\mu\text{V/V}$		
295	A	P		60 kHz	$67~\mu\text{V/V}$		
296	A	P		100 kHz	$68\muV/V$		
297	A	P		200 kHz	$75\muV/V$		
298	A	P		500 kHz	279 μV/V		
299	A	P		700 kHz	720 μV/V		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	cal Quantities - DC and LF		כיול – גדלים חשמליים - זרם ישר ותדר נמוך		
300	A	P		1 MHz	720 µV/V		
301	A	P		50 MHz	20 mV/V		
				3 V			
302	A	P		10 Hz	$130~\mu\text{V/V}$		
303	A	P		40 Hz	$35~\mu V/V$		
304	A	P		1 kHz	$30\mu V/V$		
305	A	P		30 kHz	$32\mu V/V$		
306	A	P		50 kHz	$67~\mu V/V$		
307	A	P		100 kHz	$66\mu V/V$		
308	A	P		200 kHz	75 μV/V		
309	A	P		500 kHz	$270~\mu\text{V/V}$		
310	A	P		700 kHz	$710~\mu\text{V/V}$		
311	A	P		1 MHz	76 μV/V		
312	A	P		5 kHz	20 mV/V		
313	A	P		10 MHz	20 mV/V		
314	A	P		20 MHz	$20~\mathrm{mV/V}$		
315	A	P		30 MHz	20 mV/V		
313	A	1		30 MHZ	20 111 77 7		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	cal Quantities - DC and LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
				5 V			
316	A	P		1 kHz	28 μV/V		
				10 V			
317	A	P		10 Hz	47 μV/V		
318	A	P		40 Hz	$30\mu V/V$		
319	A	P		1 kHz	28 μV/V		
320	A	P		30 kHz	29 μV/V		
321	A	P		50 kHz	66 μV/V		
322	A	P		60 kHz	66 µV/V		
323	A	P		100 kHz	66 μV/V		
324	A	P		200 kHz	73 μV/V		
325	A	P		500 kHz	270 μV/V		
326	A	P		700 kHz	710 µV/V		
327	A	P		1 MHz	710 μV/V		
				20 V			
328	A	P		500 kHz	270 μV/V		
329	A	P		700 kHz	710 µV/V		
330	A	P		1 MHz	710 μV/V		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibre	ation –	Electri	cal Quantities - DC and LF	. ,		רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
				30 V			
331	A	P		10 Hz	$130~\mu V/V$		
332	A	P		40 Hz	$38\mu V/V$		
333	A	P		1 kHz	$30\mu\text{V/V}$		
334	A	P		30 kHz	$30\mu V/V$		
335	A	P		50 kHz	$66\mu V/V$		
336	A	P		100 kHz	$76\mu V/V$		
337	A	P		200 kHz	$110\;\mu\text{V/V}$		
				100 V			
338	A	P		10 Hz	$49~\mu\text{V/V}$		
339	A	P		40 Hz	$42~\mu\text{V/V}$		
340	A	P		1 kHz	$29\mu\text{V/V}$		
341	A	P		30 kHz	$29 \; \mu V/V$		
342	A	P		50 kHz	$66\mu V/V$		
343	A	P		60 kHz	$66\mu V/V$		
344	A	P		100 kHz	$67~\mu\text{V/V}$		
				300 V			
345	A	P		45 Hz	$45~\mu\text{V/V}$		
346	A	P		1 kHz	$43\mu V/V$		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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#### **Schedule of Accreditation**

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Item	Scope Type	Site	Measurand Inst	rument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electri	cal Quantities - DC and	LF			רם ישר ותדר נמוך	ביול – גדלים חשמליים - ז
347	A	P			5 kHz	$47~\mu\text{V/V}$		
348	A	P			10 kHz	$43\mu\text{V/V}$		
349	A	P			15 kHz	$43~\mu\text{V/V}$		
350	A	P			20 kHz	$43~\mu V/V$		
351	A	P			33 kHz	$100~\mu V/V$		
352	A	P			50 kHz	$130~\mu V/V$		
353	A	P			100 kHz	$160~\mu V/V$		
					500 V			
354	A	P			100 kHz	$160~\mu\text{V/V}$		
					700 V			
355	A	P			50 kHz	$160~\mu V/V$		
					1000 V			
356	A	P			45 Hz	$45~\mu V/V$		
357	A	P			1 kHz	$45\;\mu\text{V/V}$		
358	A	P			5 kHz	$45~\mu V/V$		
359	A	P			10 kHz	$49\mu V/V$		
360	A	P			15 kHz	$49\mu V/V$		
361	A	P			20 kHz	$49\mu\text{V/V}$		
362	A	P			30 kHz	$110~\mu\text{V/V}$		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Go	uge Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibra	ation –	Electri	ical Quantities - DC and LF			ביול – גדלים חשמליים - זרם ישר ותדר נמוך		
363	A	P		33 kH	z 110 μV/V			
				[0.9 mV to 3.0 mV]				
364	A	P		(40 Hz to 200 kHz	490 μV/V			
365	A	P		(200 kHz to 500 kHz	1.4 mV/V			
366	A	P		(500 kHz to 1 MHz	3.3 mV/V			
				(3.0 mV to 9 mV]				
367	A	P		[40 Hz to 200 kHz	$350 \mu\text{V/V}$			
368	A	P		(200 kHz to 500 kHz	1.1 mV/V			
369	A	P		(500 kHz to 1 MHz	2.6 mV/V			
				(9 mV to 30 mV]				
370	A	P		[40 Hz to 200 kHz	220 μV/V			
371	A	P		(200 kHz to 500 kHz	620 μV/V			
372	A	P		(500 kHz to 1 MHz	1.6 mV/V			
				(30 mV to 350 mV]				
373	A	P		[40 Hz to 200 kHz	150 μV/V			
374	A	P		(200 kHz to 500 kHz	$340 \mu V/V$			
375	A	P		(500 kHz to 1 MHz	860 μV/V			
				(350 mV to 35 V]				
376	A	P		[40 Hz to 200 kHz	120 μV/V			

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests: Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electri	ical Quantities - DC and LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
377	A	P		(200 kHz to 500 kHz]	330 μV/V		
378	A	P		(500 kHz to1 MHz]	860 μV/V		
				[1 V to 3.5 V]			
379	A	P		1 MHz to 30 MHz	20 mV/V		
				(35 V to 120 V]			
380	A	P		10 Hz to 100 kHz	$85~\mu V/V$		
				(120 V to 500 V]			
381	A	P		45 Hz to 100 kHz	180 μV/V		
				(500 V to 700 V]			
382	A	P		45 Hz to 50 kHz	$180~\mu\text{V/V}$		
				(700 V to 1000 V]			
383	A	P		45 Hz to 33 kHz	130 μV/V		
				[1 mV to 2 mV]			
384	A	T		[40 Hz to 100 kHz]	9 mV/V		
385	A	Т		(100 kHz to 300 kHz]	14 mV/V		
386	A	Т		(300 kHz to 1 MHz]	43 mV/V		
				(2 mV to 5 mV]			
387	A	T		[40Hz to 100 kHz]	9.6 μV		
388	A	T		(100 kHz to 300 kHz]	18 μV		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electri	cal Quantities - DC and LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
389	A	Т		(300 kHz to 1 MHz]	69 μV		
				(5 mV to 10 mV]			
390	A	T		[40 Hz to 100 kHz]	14 μV		
391	A	T		(100 kHz to 300 kHz]	22 μV		
392	A	T		(300 kHz to 1 MHz]	14 mV/V		
				(10 mV to 20 mV]			
393	A	T		[40 Hz to 100 kHz]	1.4 mV/V		
394	A	T		(100 kHz to 300 kHz]	2.2 mV/V		
395	A	Т		(300 kHz to 1 MHz]	10 mV/V		
				(20 mV to 50 mV]			
396	A	T		[40 Hz to 100 kHz]	0.92 mV/V		
397	A	T		(100 kHz to 300 kHz]	2.5 mV/V		
398	A	Т		(300 kHz to 1 MHz]	430 μV		
				(50 mV to 100 mV]			
399	A	T		[40 Hz to 100 kHz]	580 μV/V		
400	A	T		(100 kHz to 300 kHz]	1.6 mV/V		
401	A	Т		(300 kHz to 1 MHz]	8.5 mV/V		
				(100 mV to 200 mV]			
402	A	T		[40 Hz to 100 kHz]	480 μV/V		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibro	ation –	Electri	cal Quantities - DC and LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
403	A	T		(100 kHz to 300 kHz]	1.4mV/V		
404	A	Т		(300 kHz to 1 MHz]	620 μV/V		
				(200 mV to 500 mV]			
405	A	T		[40 Hz to 100 kHz]	$490\;\mu V/V$		
406	A	T		(100 kHz to 300 kHz]	0.54 mV		
407	A	Т		(300 kHz to 1 MHz]	7.9 mV/V		
				(500 mV to 1 V]			
408	A	T		[40 Hz to 100 kHz]	3.9 mV/V		
409	A	Т		(100 kHz to 300 kHz]	1.1mV/V		
410	A	Т		(300 kHz to 1 MHz]	5.3mV/V		
				(1 V to 2 V]			
411	A	T		[40 Hz to 100 kHz]	$360~\mu\text{V/V}$		
412	A	Т		(100 kHz to 300 kHz]	$900\mu\text{V/V}$		
413	A	Т		(300 kHz to 1 MHz]	4.5 mV/V		
				(2 V to 5 V]			
414	A	T		[40 Hz to 100 kHz]	4.8 mV/V		
415	A	Т		(100 kHz to 300 kHz]	1.7 mV/V		
416	A	T		(300 kHz to 1 MHz]	7.8 mV/V		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electri	cal Quantities - DC and LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
				(5 V to 10 V]			
417	A	T		[40 Hz to 100 kHz]	0.38 mV/V		
418	A	Т		(100 kHz to 300 kHz]	1 mV/V		
419	A	Т		(300 kHz to 1 MHz]	5.2 mV/V		
				(10 V to 20 V]			
420	A	T		[40 Hz to 100 kHz]	$350~\mu\text{V/V}$		
421	A	Т		(100 kHz to 300 kHz]	840 μV/V		
422	A	Т		(300 kHz to 1 MHz]	4.4 mV/V		
				(20 V to 50 V]			
423	A	T		[40 Hz to 30 kHz]	330 μV/V		
424	A	T		(30 kHz to 100 kHz]	920 μV/V		
				(50 V to 100 V]			
425	A	Т		[40 Hz to 30 kHz]	210 μV/V		
426	A	T		(30 kHz to 100 kHz]	870 μV/V		
				(100 V to 200 V]			
427	A	T		[40 Hz to 30 kHz]	180 μV/V		
428	A	Т		(30 kHz to 100 kHz]	860 μV/V		
				(200 V to 500 V]			
429	A	T		40 Hz to 33 kHz	370 μV/V		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electri	ical Quantities - DC and	LF	,		ם ישר ותדר נמוך	כיול – גדלים חשמליים - זר
					(500 V to 1000 V]			
430	A	Т			40 Hz to 33 kHz	$300~\mu V/V$		
431	A	P	AC Current Measuring Instruments	זרם חילופין מכשירי מדידה	1 mA 300 Hz	240 μΑ/Α	Manufacturer instructions SOP 10574	AVMS Datron 4920, Shunt Adapter Datron 4921, Shunt
432	A	P			1 kHz	240 μA/A		adapter Rafael 4921R, Current Shunt A40, A40A, Datron Calibrator 4808,
433	A	P			5 kHz	240 μΑ/Α		Datron 4600, Datron 9100, Current coils
434	A	P			10 mA 300 Hz	235 μΑ/Α		
435	A	P			1 kHz	235 μΑ/Α		
436	A	P			5 kHz	235 μΑ/Α		
					100 mA			
437	A	P			300 Hz	235 μΑ/Α		
438	A	P			1 kHz	235 μΑ/Α		
439	A	P			5 kHz	235 μΑ/Α		
440	A	P			1 A 300 Hz	245 μΑ/Α		
441	A	P			1 kHz	245 μΑ/Α		
442	A	P			5 kHz	245 μΑ/Α		
					10 A			
443	A	P			300 kHz	360 μΑ/Α		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instr	rument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electri	ical Quantities - DC and I	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
444	A	P			1 kHz	360 μΑ/Α		
445	A	P			5 kHz	$360~\mu\text{A/A}$		
					[1 mA to 2 mA]			
446	A	P			[10 Hz to 1 kHz]	$240~\mu\text{A/A}$		
447	A	P			(1 kHz to 5 kHz]	$250~\mu\text{A/A}$		
					(2 mA to 5 Ma]			
448	A	P			[10 Hz to 1 kHz]	$370~\mu\text{A/A}$		
449	A	P			(1 kHz to 5 kHz]	$400~\mu\text{A/A}$		
					(5 mA to 20 Ma]			
450	A	P			[10 Hz to 1 kHz]	255 μΑ/Α		
451	A	P			(1 kHz to 5 kHz]	$280~\mu\text{A/A}$		
					(20 mA to 50 mA]			
452	A	P			[10 Hz to 1 kHz]	$380~\mu\text{A/A}$		
453	A	P			(1 kHz to 5 kHz]	$410\mu\text{A/A}$		
					(50 mA to 200 mA]			
454	A	P			[10 Hz to 1 kHz]	$260~\mu\text{A/A}$		
455	A	P			(1 kHz to 5 kHz]	$285~\mu\text{A/A}$		
					(200 mA to 500 mA]			
456	A	P			[10 Hz to 1 kHz]	$490~\mu\text{A/A}$		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח מנות ומספרה ומספר הנספח ומספר הנספח ומספרה ומספר הנספח ומספרה ומספר הנספח ומספרה ומספר הנספח ומספרה ומספרה

# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibre	ation –	Electri	cal Quantities - DC and LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
457	A	P		(1 kHz to 5 kHz]	660 μΑ/Α		
				(500 mA to 2 A]			
458	A	P		[10 Hz to 1 kHz]	360 µA/A		
459	A	P		(1 kHz to 5 kHz]	485 μA/A		
				(2 A to 11 A]			
460	A	P		[10 Hz to 1 kHz]	400 μΑ/Α		
461	A	P		(1 kHz to 5 kHz]	460 μA/A		
				(11 A to 20 A]			
462	A	P		[10 Hz to 3 kHz]	2.1 mA/A		
463	A	P		(3 kHz to 5 kHz]	6 mA/A		
				(20 A to 200 A]			
464	A	P		[10 Hz to 100 Hz]	2.6 mA/A		
465	A	P		(100 Hz to 440 Hz]	8 mA/A		
				(200 A to 1000 A]		Manufacturer instructions	Fluke 5730A
466	A	P		[10 to100 Hz]	4 mA/A	SOP 10700	Datron 4600
				[1 mA to 2 mA]			Datron 9100
467		Т		[10 Hz to 1 kHz]	620 μA/A		Current coils
	A						
468	A	T		(1 kHz to 5 kHz]	720 μA/A		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	ical Quantities - DC and LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
				(2 mA to 5 mA]			
469	A	T		[10 kHz to 1 kHz]	1.3 mA/A		
470	A	Т		(1 kHz to 5 kHz]	1.4 mA/A		
				(5 mA to 20 mA]			
471	A	T		[10 Hz to 1 kHz]	0.8 mA/A		
472	A	Т		(1 kHz to 5 kHz]	0.9 mA/A		
				(20 mA to 50 mA]			
473	A	Т		[10 Hz to 1 kHz]	1.3 mA/A		
474	A	T		(1 kHz to 5 kHz]	1.4 mA/A		
				(50 mA to 200 mA]			
475	A	T		[10 Hz to 1 kHz]	0.8 mA/A		
476	A	T		(1 kHz to 5 kHz]	0.9 mA/A		
				(200 mA to 500 mA]			
477	A	Т		[10 Hz to 1 kHz]	1.5 mA/A		
478	A	T		(1 kHz to 5 kHz]	1.7 mA/A		
				(500 mA to 2 A]			
479	A	Т		[10 Hz to 1 kHz]	0.96 mA/A		
480	A	T		(1 kHz to 5 kHz]	1.3 mA/A		
	1						

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	ical Quantities - DC and	LF	, ,		רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
					(2 A to 11 A]			
481	A	T			[10 Hz to 1 kHz]	0.86 mA/A		
482	A	T			(1 kHz to 5 kHz]	1.6 mA/A		
					(11 A to 20 A]			
483	A	Т			[10 Hz to 3 kHz]	2.1 mA/A		
484	A	T			(3 kHz to 5 kHz]	6.0 mA/A		
					(20 A to 200 A]			
485	A	T			[10 Hz to 100 kHz]	2.6 mA/A		
486	A	T			(100 Hz to 440 Hz]	8.0 mA/A		
					(200 A to 1000 A]			
487	A	T			[10 Hz to 100 Hz]	4 mA/A		
			AC Current	זרם חילופין	1 mA		Manufacturer instructions	Alternating Voltage
488	A	P	Sources	מחוללים	300 Hz	$240\mu\text{A/A}$	SOP 10570	Measurement, Datron 4920, Shunt Adapter Datron 4921,
489	A	P			1 kHz	$240~\mu\text{A/A}$	SOP 10572 SOP 10576	Shunt Adapter Rafael 4921R, Current Shunt A40,
490	A	P			5 kHz	240 μΑ/Α	SOP 10650	A40A, Wavetek MTS 4950, Datron Calibrator 4808,
					10 mA			Datron 4600, Datron 9100, Current Clamp, Current coils
491	A	P			300 Hz	240 μΑ/Α		Current Clamp, Current Cons
492	A	P			1 kHz	240 μΑ/Α		
493	A	P			5 kHz	240 μA/A		
+23	A	1			J KIIZ	210 11211		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests: Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.

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#### Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibro	ation –	Electri	cal Quantities - DC and LF	J (		רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
				100 mA			
494	A	P		300 Hz	240 μΑ/Α		
495	A	P		1 kHz	240 μΑ/Α		
496	A	P		5 kHz	240 μΑ/Α		
				1 A			
497	A	P		300 Hz	240 μΑ/Α		
498	A	P		1 kHz	240 μΑ/Α		
499	A	P		5 kHz	240 μΑ/Α		
				10 A			
500	A	P		300 Hz	350 µA/A		
501	A	P		1 kHz	350 μΑ/Α		
502	A	P		5 kHz	350 μΑ/Α		
				[1 mA to 2 mA]			
503	A	P		[10 Hz to 49 Hz]	240 μΑ/Α		
504	A	P		[51 Hz to 1 kHz]	240 μΑ/Α		
505	A	P		(49 Hz to 51 Hz)	490 μΑ/Α		
				(2 mA to 5 mA]			
506	A	P		[10 Hz to 49 Hz]	380 μΑ/Α		
507	A	P		[51 Hz to 1 kHz]	400 μA/A		
508	A	P		(49 Hz to 51 Hz)	510 μA/A		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically המעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electri	cal Quantities - DC and LF		כיול – גדלים חשמליים - זרם ישר ותדר נמוך		
				(5 mA to 20 mA]			
509	A	P		[10 Hz to 49 Hz]	260 μΑ/Α		
510	A	P		[51 Hz to 1 kHz]	$260~\mu\text{A/A}$		
511	A	P		(49 Hz to 51 Hz)	310 μΑ/Α		
				(20 mA to 50 mA]			
512	A	P		[10 Hz to 1 kHz]	$420~\mu\text{A/A}$		
513	A	P		(1 kHz to 5 kHz]	425 μA/A		
				(50 mA to 200 mA]			
514	A	P		[10 Hz to 1 kHz]	270 μΑ/Α		
515	A	P		(1 kHz to 5 kHz]	290 μΑ/Α		
				(200 mA to 500 mA]			
516	A	P		[10 Hz to 1 kHz]	$500\mu\text{A/A}$		
517	A	P		(1 kHz to 5 kHz]	670 μΑ/Α		
				(500 mA to 2 A]			
518	A	P		[10 Hz to 1 kHz]	370 μΑ/Α		
519	A	P		(1 kHz to 5 kHz]	490 μΑ/Α		
				(2 A to 11 A]			
520	A	P		[10 Hz to 1 kHz]	$400~\mu\text{A/A}$		
521	A	P		(1 kHz to 5 kHz]	$460~\mu\text{A/A}$		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח מה למספר הנספח ומספרה ומספרה ומספרה הנספח ומספרה ו

# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibr	ation –	Electri	ical Quantities - DC and	LF		כיול – גדלים חשמליים - זרם ישר ותדר נמוך			
					(11 A to 20 A]				
522	A	P			[10 Hz to 3 kHz]	2.1 mA/A			
523	A	P			(3 kHz to 5 kHz]	6.0 mA/A			
					(20 A to 200 A]				
524	A	P			[10 Hz to 100 Hz]	2.6 mA/A			
525	A	P			(100 Hz to 440 Hz]	8.0 mA/A			
					(200 A to 1000 A]				
526	A	P			[10 to 100 Hz]	4.0 mA/A			
527	A	P	AC Resistance, Measuring	התנגדות זרם חילופין, מכשירי	10 Ω		Manufacturer instructions	HP AC Resistors	
			Instruments	מדידה	100 kHz	$1.5~\mathrm{m}\Omega/\Omega$	SOP 10980		
528	A	P			100 Ω				
520		P			$100~\mathrm{kHz}$ 1 k $\Omega$	$1.5~\mathrm{m}\Omega/\Omega$			
529	A	Р			1 K52 100 kHz	2.3 mΩ/Ω			
530	A	P			10 kΩ				
220					100 kHz	$2.3~\mathrm{m}\Omega/\Omega$			
531	A	P			100 kΩ				
					100 kHz	$3.5~\mathrm{m}\Omega/\Omega$			
532	A	P			10 Ω	15.00			
522	_	D			1 MHz 100 Ω	$1.5~\mathrm{m}\Omega/\Omega$			
533	A	P			1 MHz	1.5 mΩ/Ω			
534	A	P			1 kΩ				
					1 MHz	2.3 mΩ/Ω			

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electri	ical Quantities - DC and LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
535	A	P		10 kΩ 1 MHz	2.3 mΩ/Ω		
536	A	P		10 Ω			
537	A	P		$10~\mathrm{MHz}$ $100~\Omega$	2.1 mΩ/Ω		
720		-		$10\mathrm{MHz}$ $1\mathrm{k}\Omega$	3.5 mΩ/Ω		
538	A	P		10 MHz	3.5 mΩ/Ω		
539	A	P	AC Resistance, Resistors מחוללים	$10~\Omega$ $100~\text{kHz}$	$1.5~\mathrm{m}\Omega/\Omega$	Manufacturer instructions SOP 10985	LCR HP AC Resistors
540	A	P		100 Ω $100~\rm kHz$	$1.5~\mathrm{m}\Omega/\Omega$		
541	A	P		1 kΩ			
542	A	P		$100~\text{kHz}$ $10~\text{k}\Omega$	$2.3~\mathrm{m}\Omega/\Omega$		
543	A	P		$100~\mathrm{kHz}$ $100~\mathrm{k}\Omega$	$2.3~\mathrm{m}\Omega/\Omega$		
343	A	1		100 kHz	$3.5~\mathrm{m}\Omega/\Omega$		
			Capacitance, Measuring קיבול, מכשירי מדידה Instruments	10 nF		Manufacturer instructions	HP Standard Capacitors
544	A	P		120 Hz	0.4 mF/F	SOP 10980	GR standard Capacitors
545	A	P		1 kHz	0.4 mF/F		
546	A	P		10 kHz	0.6 mF/F		
547	A	P		100 kHz	1.6 mF/F		

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#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument,	Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibre	ation –	Electri	cal Quantities - DC and LF				רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
					100 nF			
548	A	P			120 Hz	0.4 mF/F		
549	A	P			1 kHz	0.3 mF/F		
550	A	P			10 kHz	1 mF/F		
551	A	P			100 kHz	3 mF/F		
					1 μF			
552	A	P			120 Hz	0.6 mF/F		
553	A	P			1 kHz	0.3 mF/F		
554	A	P			10 kHz	0.8 mF/F		
					1 pF			
555	A	P			1 kHz	2 mF/F		
556	A	P			1 MHz	4 mF/F		
557	A	P			10 MHz	13 mF/F		
558	A	P			13 MHz	13 mF/F		
					10 pF			
559	A	P			1 kHz	0.3 mF/F		
560	A	P			1 MHz	0.8 mF/F		
561	A	P			10 MHz	2.5 mF/F		
562	A	P			13 MHz	2.5 mF/F		

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#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instr	rument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	ical Quantities - DC and I	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
					100 pF			
563	A	P			1 kHz	0.6 mF/F		
564	A	P			1 MHz	0.6 mF/F		
565	A	P			10 MHz	2 mF/F		
566	A	P			13 MHz	2 mF/F		
					1000 pF			
567	A	P			1 kHz	0.3 mF/F		
568	A	P			1 MHz	0.5 mF/F		
569	A	P			10 MHz	6 mF/F		
570	A	P			13 MHz	6 mF/F		
			Capacitance, Capacitors	קיבול, קבלים	10 nF		Manufacturer instructions	LCR
571	A	P			120 Hz	0.4 mF/F	SOP 10985	HP Standard Capacitors
572	A	P			1 kHz	0.4 mF/F		GR Capacitors
573	A	P			10 kHz	0.6 mF/F		
574	A	P			100 kHz	1.6 mF/F		
					100 nF			
575	A	P			120 Hz	0.4 mF/F		
576	A	P			1 kHz	0.3 mF/F		
577	A	P			10 kHz	1 mF/F		
578	A	P			100 kHz	3 mF/F		

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Inst	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	cal Quantities - DC and	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - זו
					1 μF			
579	A	P			120 Hz	0.6 mF/F		
580	A	P			1 kHz	0.3 mF/F		
581	A	P			10 kHz	0.8 mF/F		
582	A	P			1 pF 1 kHz	2 mF/F		
583	A	P			10 pF 1 kHz	0.3 mF/F		
584	A	P			100 pF 1 kHz	0.6 mF/F		
585	A	P			1000 pF			
					1 KHz	0.3 mF/F		
586	A	P	Inductance, Measuring Instruments	השראות, מכשירי מדידה	100 μH 1 KHz	0.7 mF/F	Manufacturer instructions SOP 10980	GR Inductors
587	A	P			1 mH	0.0 . 177		
588	A	P			1 KHz 10 mH	0.3 mF/F		
					1 KHz	0.4 mF/F		
589	A	P			100 mH 1 kHz	0.3 mF/F		
590	A	P			1 H			
591	A	Р			1 kHz 10 H	0.6 mF/F		
331	A	1			400 Hz	0.5 mF/F		

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח מה למספר הנספח ומספרה ומספרה ומספרה הנספח ומספרה ו

#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	ical Quantities - DC and	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - זי
592 593 594 595	A A A	P P P	Inductance, Inductors	השראות, משרנים	100 μH  1 kHz  1 mH  1 kHz  10 mH  1 kHz  10 kHz  10 kHz	0.7 mF/F  0.3 mF/F  0.4mF/F	Manufacturer instructions SOP 10985	LCR GR Tech Inductors
596 597	A A	P P			1 H 1 kHz 10 H 400 Hz	0.7 mF/F		
598 599 600 601 602 603 604	A A A A A	P P P P;T P;T	Frequency, Sources	תדר, מחוללים	100 kHz  1 MHz  5 MHz  10 MHz  [1 Hz to 10 kHz]  (10 kHz to 30 MHz]  (30 MHz to 80 MHz]	10 <sup>-11</sup> for 3 h 10 μHz for 1 s 10 <sup>-9</sup> for 1 s	Manufacturer instructions SOP 10907	d -stays for days Oscillator HP 105B Comparator Fluke 103A GPS HP 58503A

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The certificate attached is an integral part of the schedule and is numbered identically המעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המשרח ומספרה המצורפת לנספח ומספרה המצורפת לנספח וה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח המשרח ומספרה הנספח המשרח ומספרה הנספח ומספרה המשרח ומספרה הנספח ומספרה ומספרה הנספח ומספרה ומספרה

#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electri	cal Quantities - DC and	LF			רם ישר ותדר נמוך	כיול – גדלים חשמליים - ז
605	A		AC charge amplification. Charge amplifiers		40 Hz – 10 kHz Minimum input 10 pC RMS Maximum output 1 V RMS	0.2 %	Manufacturer instructions SOP 11300	Calibration of voltage output per charge input

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electri	ical Quantities - RF Frequency, Time			רר גבוה, זמן -	כיול – גדלים חשמליים <b>-</b> תי
606	A	P;T	Frequency. ,תדר,	(80 MHz to 1500 MHz]	1.2 mHz for 10 s	Manufacturer instructions	HP 105 B, HP 58503A,
607	A	P;T	מקורות	(1500 MHz to 6 GHz]	2 mHz for 10 s	SOP 10924	HP5245M, HP 3335 A, HP 3325
608	A	P;T		(6 GHz to 50 GHz]	3·10 <sup>-13</sup> for 10 s		GPS HP 58503 A
609	A	P;T	Frequency. ,תדר,	[1 Hz to 100 Hz]	25 μHz for 1 s	Manufacturer instructions	HP 105 B, HP 58503A,
610	A	P;T	Measuring Instruments מכשירי מדידה	(100 Hz to 10 kHz]	11 μHz for 1 s		HP5245M, HP 3335 A, HP 3325, GPS HP 58503 A
611	A	P;T		(10 kHz to 30 MHz]	2·10 <sup>-10</sup> for 1 s		,
612	A	P;T	Time markers function, sine מדידת דיוק ציר אופקי במשקף מנודות בעזרת גל סינוס	[0.2 ns to 1 ns]	0.21 ps	Manufacturer instructions SOP 10974	Wavetek 9500B
613	A	P;T		(1 ns to 9 ns]	1.8 ps		
614	A	P;T	Time markers function, square wave מדידת דיוק ציר אופקי במשקף תודות בעזרת גל מרובע	[10 ns to 100 µs]	0.8 ns	Manufacturer instructions	Wavetek 9500B
615	A	P;T	Square many	(100 µs to 1 ms]	1.6 ns	SOP 10974	
616	A	P;T		(1 ms to 55 s]	80 μs		
617	A	P;T	DC Voltage into מדידת דיוק ציר אנכי במשקף אנכי מחדר מחדר אנכי במשקף אנכיות בכניסה חודת בכניסה חודת בכניסה חודת בכניסה חודת בכניסה חודת בכניסה חודת מחדר אונכי מחדר אונכי היא מודת במחדר אונכי היא מחדר אונכי היא מודר אונדת היא מודר אונכי היא מודר אוני היא	1 mV to 190 V	$25~\mu\text{V} + 0.25~\text{mV/V OR}$	Manufacturer instructions SOP 10700	FLUKE 9500 & active heads OR - of reading
618	A	P;T	DC Voltage into מדידת דיוק ציר אנכי במשקף 50 $\Omega$ סרט אנכי במשקר העודות בכניסה סרט סרט העודות בכניסה	1 mV to 5V	$25 \mu V + 0.25 \text{ mV/V OR}$	Manufacturer instructions SOP 10700	
619	A	P;T	Square Wave Voltage into מדידת דיוק ציר אנכי במשקף אופר אומר מחודות בכניסה אומר אומר אומר אומר אומר אומר אומר אומר	1 kHz [6 mV to 210 V]	2.9 mV/V	Manufacturer instructions SOP 10974	

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Electr	ical Quantities - RF Fre	quency, Time			תדר גבוה, זמן	כיול – גדלים חשמליים -
620	A	P;T	Input Resistance	מדידת התנגדות כניסה של משקף תנודות	50 Ω	1 m $\Omega/\Omega$	Manufacturer instructions	
621	A	P;T			$1~\mathrm{M}\Omega$	$1~\text{m}\Omega/\Omega$	SOP 10650	
622	A	P;T	Bandwidth (50 Ω & 1 MΩ)	מדידת רוחב פס של משקף תנודות (M 1 M 2 0 05)	[1 kHz to 20 MHz] 100 mV to 3V	0.023 MHz/MHz (2.3 %)	Manufacturer instructions SOP 10974	
623	A	P;T			(20 MHz to 500 MHz] 200 mV to 2V	0.015 MHz/MHz (1.5 %)		
624	A	P;T			(500 MHz to 6 GHz] 200 mV to 2V	0.07 GHz/GHz (0.7%)		
625	A	P;T			(6 GHz to 50 GHz ] 632.5 mV	0.1 GHz/GHz (10 %)		
626	A	P;T	Input Capacitance	מדידת קיבול כניסה של משקף תנודות	18 pF to 92 pF	30 mF/F	Manufacturer instructions SOP 10650	
627	A	P;T	Transition Time, Oscilloscopes	מדידת זמן עליה של משקף תנודות	$25$ mV to $2.2$ V $$>\!\!70~ps$	5.6 ps	Manufacturer instructions SOP 10974	
628	A	P;T	Transition Time, Pulse generators	מדידת זמן עליה של מחולל אותות	$400~\mathrm{mV}$ $$>19~\mathrm{ps}$$	2.5 ps	Manufacturer instructions SOP 10974	

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#### **Schedule of Accreditation**

Item	Scope	Site	Measurand Inst	trument, Gauge	Range	CMC Expressed as an Expanded	Reference Documents	Remarks
	Type				[Including margins] (Does not include margins)	Uncertainty (95%)		
Calibr	ation –	Electri	ical Quantities – LF Sing	gle Phase Electrical Pow	er and Energy	מופעית בתדר נמוך	ספק ואנרגיה חשמלית חד	כיול – גדלים חשמליים - ה
629	A	P;T	Power,	הספק,	[10 MHz to 18 GHz]	50 mW/W	Manufacturer instructions	Reference Power Sensor
630	A	P;T	Sources	מקורות	(18 GHz to 40 GHz]	51 mW/W	SOP 10925	Reference Power Meter (1mwatt)
631	A	P;T			(40 GHz to 50 GHz]	65 mW/W		
632	A	P;T	Power,	הספק,	[100 MHz to 8 GHz]	20 mW/W	Manufacturer instructions	Reference Power Sensor
633	A	P;T	Power Sensors Cal Factor	מקדם כיול רגשי הספק	(8 GHz to 32 GHz]	30 mW/W	SOP 10945 Manufacturer instructions	
634	A	P;T			(32 GHz to 43 GHz]	35 mW/W		
635	A	P;T			(43 GHz to 50 GHz]	42 mW/W		
636	A	P;T	Power	הספק,	50 MHz	5.4 mW/W	SOP 10923	Reference Power Sensor
			Power Meter 1 mW output	מדי הספק, יציאה 1 mW				
			Attenuation, Attenuators	הנחתה מנחתים	[0.1 GHz to 2 GHz]			436A-E40 Microwave Power Sensor System
637	A	P;T			[0 dB to 15 dB]	0.04 dB	Manufacturer instructions	HP 8350B Sweep Generator
638	A	P;T			(15 dB to 35 dB]	0.09 dB	SOP 10928	HP 436A Power Meter
639	A	P;T			(35 dB to 60 dB]	0.12 dB		HP 8481A, 8484 Power References Sensors
					(2 GHz to 6 GHz]			
640	A	P;T			[0 to 15 dB]	0.06 dB		
641	A	P;T			(15 to 35 dB]	0.12 dB		
642	A	P;T			(35 to 60 dB]	0.21 dB		
					(6 GHz to 14 GHz]			
643	A	P;T			[0 dB to 15 dB]	0.08 dB		

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#### Schedule of Accreditation

Item	Scope Type	Site	Measurand Inst	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Electri	ical Quantities – LF Sing	gle Phase Electrical Pow	er and Energy	מופעית בתדר נמוך	וספק ואנרגיה חשמלית חד	כיול – גדלים חשמליים - ו
644	A	P;T			(15 dB to 35 dB]	0.19 dB		
645	A	P;T			(35 dB to 60 dB]	0.21 dB		
					(14 GHz to 18 GHz]			
646	A	P;T			[0 dB to 15 dB]	0.1 dB		
647	A	P;T			(15 dB to 35 dB]	0.13 dB		
648	A	P;T			(35 dB to 60 dB]	0.23 dB		
649	A	P;T	Amplitude Modulation (AM), Depth of Signals	אפנון משרעת, עומק אפנון	Carrier frequency: [sine 100 Hz to 50 GHz]  Modulation frequency: [1 Hz to 250 kHz sine and square]  Modulation depth: [5% to 95%]  Ratio: Carrier/Rate [10 to 50·10 <sup>9</sup> ]]	1 %	Manufacturer instructions SOP 10962	Agilent PSA spectrum Analyzer, model E4448A

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Item	Scope Type	Site	Measurand Inst	rument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Mecha	nical Quantities – Accelo	al Quantities – Accelerometers				
650	A	P	Acceleration Piezoelectric type accelerometer	מד תאוצה פייזואלקטרי	[5 m/s2 to 100 m/s2] [2 Hz to 100 Hz]	1.5 %	ISO 16063-21 SOP 10040	Back to back calibration versus standard accelerometer
651 652	A A	P P			(100 Hz – 2.5 kHz] (2.5 kHz to 10 kHz]	1.2 % 2.5 %		UUT Sensitivity range 0.004  pC/g to $50  pC/gg = 9.807 \text{ m/s}^2UUT mass up to 100 \text{ g}$
653 654 655	A A	P P	Acceleration Piezoresistive type accelerometer	מד תאוצה פייזורזיסטיבי	[5 m/s2 to 100 m/s2] [2 Hz to 100 Hz] (100 Hz – 2.5 kHz] (2.5 kHz to 10 kHz]	1.5 % 1.2 % 2.5 %	ISO 16063-21 SOP 10040	OR –of reading  Back to back calibration versus standard accelerometer  UUT Sensitivity range 0.05 mV/g to 200 mV/g g = 9.807 m/s²
					[200 m/s <sup>2</sup> to 20 000 m/s <sup>2</sup> ]	1.9 %		UUT mass up to 100 g OR –of reading
656 657	A	P P	Acceleration Piezoelectric type accelerometer Shock Calibration	מד תאוצה כיול הלם	(20 000 m/s² to 100 000 m/s²]	3.9 %	ISO 16063-22 SOP 10040	Back to back calibration versus standard accelerometer UUT Sensitivity range 1 mV/g to 20 mV/g g = 9.807 m/s <sup>2</sup> UUT mass up to 100 g OR — of reading

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibr	ation –	Mecha	anical Quantities – CMM	Measuring Machines		ו מכניים – מכשירי מדידה תלת ממדיים			
658	A	P,T	Length, CMM Measuring Machine	אורך, מכונת מדידה תלת ממדיות	20 mm to 2000 mm	11	ISO 10360-2 SOP 10025	L in meters Check Master Accurate Ball Gauge	
659	A	P,T			125 mm to 1000 mm		ISO 10360-2 SOP 10025	Gauge Blocks	

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Mecha	nical Quantities – Form	, Angle			ה, זווית	כיול – גדלים מכניים – צורו
660	A	P	Form, Flatness,	צורה, שטיחות, מישור אופטי	Up to 0.6 μm]	0.09 μm	A-A-58051 JIS B 7430	For optical flats with a diameter up to 100 mm
661	A	P	Optical Flats	מישוו אופטי	(0.6 μm to 1.2 μm]	0.12 μm	Manufacturer instructions SOP 9150104	For surfaces with a diameter up to 100 mm
662	A	P,T	Form, Flatness, Surface Plates	צורה, שטיחות, לוחות שטוחים	Up to 2 mm	2.1 μm	DIN 876 parts 1 and 2 BS 817 ASME B89.3.7 ISO 8512-part 2 SOP 10032	Electronic Levels L in meters diagonal Granite, Cast Iron For surfaces up to 2000 mm in diagonal
663	A	Р	Form, Straightness Straightedges	צורה, ישרות, סרגל ישרות	Up to 500 mm	3 µm	DIN 874 part 2 SOP 9150114	Surface plate, electronic gauge head
664	A	P	Form, Straightness, Knife edge	צורה, ישרות, סרגל שערה	Up to 500 mm	0.8 µm	DIN 874 part 2 SOP 9150121	Surface plate, electronic gauge head, Square Block

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# **Schedule of Accreditation**

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Calibr	ation –	Mech	anical Quantities – Form,	, Angle			י, זווית 	כיול – <i>גדלים מכניים – צור</i> ר
665 666	A A A	P P P	Cylindrical square  Squareness  Straightness	גליל ניצבות	Square height: Up to 100 mm] Up to 100 μm Up to 100 μm	2.1 μm 0.55 μm	BS 939 Manufacturer instructions SOP 10031	Surface plate, electronic head, V-blocks for Cylindrical Squares up to 600 mm
667	A	P	Flatness of basis		Up to 100 μm	0.41 μm		
	A	P	Cylindrical square	גליל ניצבות	Square height: (100 to 300mm]		BS 939Manufacturer instructions	Surface plate, electronic head, V-blocks
668	A	P	Squareness		Up to $100  \mu m$	3 μm	SOP 10031	for Cylindrical Squares up to
669 670	A A	P P	Straightness Flatness of basis		Up to 100 μm Up to 100 μm	0.7 μm 0.41 μm	BS 939 Manufacturer instructions SOP 10031	- 600 mm
	A	P	Cylindrical square	גליל ניצבות	Square height: (300 to 600mm]		BS 939 Manufacturer instructions	Surface plate, electronic head, V-blocks
671	A	P	Squareness		Up to 100 µm	3 μm	SOP 10031	for Cylindrical Squares up to 600 mm
672	A	P	Straightness		Up to 100 µm	1.5 µm		000 mm
673	A	P	Flatness of basis		Up to 100 μm	0.41 μm		
674	A	P	Squareness,	ניצבות זוויתן ברך	Up to 0.02 mm	1.1 μm	BS 939	Surface plate, electronic head, straightedges
675	A	P	Block square Base Parallelism	מקבילות הבסיס	Up to 200 mm	1.0 μm	Manufacturer instructions SOP 9150113	for Block Squares up to
676	A	P			(200 to 500 mm]	1.4 μm		500 mm

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח



# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Inst	rument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Mech	anical Quantities – Form	Angle			, זווית	כיול – <i>גדלים מכניים – צורה</i>
677	A	P	Squareness Squareness gauge	ניצבות מד ניצבות	Up to 600 mm	3.5 μm	Manufacturer instructions SOP 9150113	Cylindrical square
678	A	P	Parallelism, Parallels, Steel and Granite	מקבילות, מקבילי פלדה וגרניט	Up to 400 mm	1.1 μm	DIN 6346 GGG-P-61 BS 906 part 1 and 2 SOP 9150122	Surface plate, electronic head
679	A	P	Angle, Vee Blocks Squareness, Flatness and Parallelism	זווית, פריזמה V	Up to 200 mm	1.0 μm	DIN 2274 BS 3731 A-A-51150B SOP 9150117	Accurate cylinders, surface plate, electronic head
680	A	P	Angle, Small angle generator	זווית, מיצר זוויות קטנות	Up to 200 min	1.4"	Manufacturer instructions SOP 10035	Gauge blocks, autocollimator
681 682	A A	P P	Bevel Protractor Angle Straightness, parallelism	מד זווית זווית, ישרות, מקבילות	360°	1.1 ' 2.5 μm	BS 1685 A-A-3084 SOP 9150114	Angular block gauges
683	A	P	Angle, Levels, spirit	זווית, פלס	Up to 0.02 mm/m	1.2"	DIN 877 BS 958 MIL-V-3144B SOP 9150118	Small angle generator
684	A	P	Angle, Rotary table	זווית, שולחן מסתובב	Up to 360°	1.2"	Manufacturer instructions SOP 9150130	Autocollimator, polygon
685	A	P	Angle, Electronic levels	זווית, פלס אלקטרוני	Up to 400"	1.5"	DIN 877 BS 958	Small angle generator

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Mecha	anical Quantities – Form	ı, Angle			ו, זווית	כיול – <i>גדלים מכניים – צור</i> ר
686	A	P	Angle, Digital Levels	זווית, פלס אלקטרוני פלס דיגיטלי	Up to 360°	2.9'	MIL-V-3144B Manufacturer instructions SOP 9150118	
687 688	A A	P P	Sine Bar  Parallelism of roll axes	סרגל סינוס מקבילות בין צירי הגליל	0° -45° 0° -45°	6.3 " 0.7 μm	BS 3064 SOP 9150119	Gauge blocks, angle gauge blocks
689	A	P	Flatness of working surface	שטיחות משטח עבודה	0° -45°	0.8 μm		
690	A	P	Parallelism of working surface to reference plane	מקבילות בין משטחי עבודה למישור הייחוס	0° -45°	0.8 µm		
691	A	P	Distance between roll axes	מרחק בין צירי הגלילים	0° -45°	3.8 µm	SOP 9150119	
692	A	P	Inclinometer	מד שיפוע	45 °	3.1"	Manufacturer instructions SOP 10027	Sine bar, gauge blocks, DVM
693 694	A A	P P	Revolution per minute Contact Tachometers	מהירות סיבוב, מד מהירות סיבוב במגע	[100 to 500] RPM (500 to 10000] RPM	0.6% OR 0.03% OR	Manufacturer instructions SOP 10044	Counter OR –of reading
695 696	A A	P P	Revolution per minute Optical Tachometers	מהירות סיבוב, מד מהירות סיבוב אופטי	[5 to 10,000] RPM (10,000 to 100,000] RPM	0.05% OR 0.02% OR	Manufacturer instructions SOP 10044	Counter OR –of reading

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Calibr	ation –	Mecha	nical Quantities - Hardness	Meters			קושיות	כיול – גדלים מכניים - מדי
697	A	P,T	Rockwell hardness scale,	קשיות רוקוול,	HRA		ASTM E-18	Indirect verification, i.e.
698	A	P,T	Rockwell hardness testing machines	מכונות לבדיקת קשיות רוקוול	[20 to 84] HRC	0.4 HRA	SOP 10018	Calibration by comparison to reference materials.
					[20 to 65]	0.4 HRC		
699	A	P,T			HRBW [40 to 100]	1.0 HRBW		
700	A	P,T			HREW [70 to 100]	0.55 HREW		
701	A	P,T			HRFW [60 to 100]	0.5 HRFW		
702	A	P,T			HR15N [70 to 92]	0.5 HR15N		
703	A	P,T			HR30N [42 to 82]	0.5 HR30N		
704	A	P,T			HR15TW [74 to 93]	0.4 HR15TW		
705	A	P,T			HR30TW			
, 02		-,-			[43 to 83]	0.7 HR30TW		
706	A	P	Shore hardness testing instruments - durometers. SHORE A	מכשירים למדידת קשיות בשיטת שור - דורמטרים. שור A	[0 to 100] Shore A	0.5 SHORE A	ASTM D-2240 ISO 18898 SOP 10028	Balance and device for durometer calibration Profile projector
707	A	P	Indenter extension	אורך החודרן	[2.46 to 2.54] mm	0.045 mm	10020	
708	A	P	Indenter diameter	קוטר החודרן	[0.76 to 0.82] mm	0.002 mm		
709	A	P			[1.1 to 1.4] mm	0.002 mm		
710	A	P	Indenter angle	זווית החודרן	[34.75° to 35.25°]	0.07°		

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Item	Scope Type	Site	Measurand Inst	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	Calibration – Mechanical Quantities - Hardness Meters						קושיות	כיול – גדלים מכניים - מדי
711	A	P	Shore hardness testing instruments - durometers. SHORE D	מכשירים למדידת קשיות בשיטת שור - דורמטרים. שור D	[10 to 100] Shore D	0.3 SHORE D	ASTM D-2240 ISO 18898 SOP 10028	Balance and device for durometer calibration Profile projector
712	A	P	Indenter extension	אורך החודרן	[2.46 to 2.54] mm	0.045 mm	501 10020	
713	A	P	Indenter diameter	קוטר החודרן	[1.1 to 1.4] mm	0.002 mm		
714	A	P	Indenter radius	רדיוס החודרן	[0.088 to 0.112] mm	0.002 mm		
715	A	P	Indenter angle	זווית החודרן	[29.5° to 30.5°]	0.07°		

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Item	Scope Type	Site	Measurand Inst	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Mecha	nical Quantities - Lengt	h			_	כיול – גדלים מכניים - אורך
716 717 718 719	A A A	P P P	Length, Gauge Blocks (by Comparison)	אורך, מקבילונים	[0.5 mm to 10 mm] (10 mm to 25 mm] (25 mm to 60 mm]	#A ##B 0.085 μm 0.15 μm 0.11 μm 0.18 μm 0.14 μm 0.22 μm 0.19 μm 0.27 μm	SOP 9150112  Based on  DIN 861  JIS B 7506  BS 4311  ISO 3650	Gauge Block Comparator # Class A uncertainties apply to the measurement of length of gauges by comparison with grade K standards of a similar material
720 721	A A	P P			(90 mm to 100 mm] (100 mm up to 250 mm]	0.25 μm 0.34 μm 0.55 μm	150 3030	## Class B uncertainties apply to the measurement of length of gauges by comparison with grade 0 standards of a similar material
722	A	P	Length, Gauge Blocks Comparators	אורך, קומפרטור למקבילונים	[0.5 mm to 250 mm]	[0.05 + 0.3L] μm	SOP 10053 Based on EURAMET/cg-02	Set of 6 pairs of gauge blocks including 6 mm bridge shaped gauge block Grade K gauge blocks L in meters
723	A	P	Length,	אורך, מוטות הארכה למיקרומטר	[25 mm to 600 mm]	0.5 μm	GGG-C-105-1987 DIN 861-1980	Gauge block,
724	A	P	Micrometer extension rod	בו טווניואו בוו כני קו ונטו	(25 mm to 1000 mm]	[1 + 1.2L] μm	SOP 9150127	Measuring machines L in meters
725	A	P	Diameter, Plain Ring Gauges, parallel	קוטר, מדידי טבעת חלקה	[1.5 mm to 90 mm]	0.3 μm	SOP 9150123 Based on DIN 2250 part 1 DIN 2250 part 2	Gauge Blocks Measuring machines
726	A	P			(90 mm to 300 mm]	0.4 μm	DIN 2254 DIN 2254 DIN 7162	

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Item	Scope Type	Site	Measurand Inst	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Mecha	nical Quantities - Lengt	h				כיול – <i>גדלים מכניים - אור</i> ך
							DIN 7163 ASME B1.1 ASME B1.2	
727 728	A A	P P	Diameter, Plain Plug Gauges	אורך, (קוטר) מדידי תקע חלק	[0.7 mm to 25 mm] (25 mm to 200 mm]	1.0 μm 1.0 μm	SOP 10050 Based on MIL-STD-120 DIN 7164 ASME B1.1, ASME B1.2	Gauge Blocks Measuring machines
729	A	P	Diameter, Measuring Pins	אורך (קוטר), מדידי קדח	[0.7 mm to 25.4 mm]	0.8 μm	MIL-STD-120 DIN 2269 SOP 10050	Gauge Blocks Measuring machines
730	A	P	Diameter, Pitch. Thread Measuring Wires,	קוטר, תיילים למדידת הברגה	[0.1155 mm to 5.7735 mm]	0.3 μm	ASME B89.6 SOP 10048	Measuring machine
731	A	P	Diameter, Pitch. Thread Plug Gauges, Parallel	קוטר, מדידי הברגה זכר מקביל	[0.8mm to 300 mm]	1 μm	ISO 228/1/2 ISO 1502 ISO 2903 ISO 2904 BS 84 BS 919/1/3 409/1/2 ASMEB1.2 ASME B1.1 ASME B1.9 SOP 9150124	Gauge Blocks Measuring machine

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	e	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Mecha	nical Quantities - Length					כיול – <i>גדלים מכניים - אורך</i>
732	A	P	Diameter, Titem	קוטר אפקטיבי, מדידי הברגה זכו	[0.8 mm to 77 mm]	3.9 µm	SOP 9150124	Flank angle 60°
733	A	P	Diameter, Titen	קוטר אפקטיבי, מדידי הברגה טב	[5 mm to 200 mm]	1.8 µm	ISO 228/1/2 ISO 1502 ISO 2903 ISO 2904 BS 84 BS 919/1/2/3 ASME B1.1, ASME B1.2 ASME B1.9 SOP 9150128	Functional Inspection (GO-NOT GO) in the range up to 25.4 mm may be provided Wear and setting plugs Measuring machine, gauge blocks
734	A	P		קוטר פנימי, מד י מובנה, אינטרטס	Up to 150 mm	8.4 μm	Manufacturer instructions JIS 7515 SOP 10014	Measuring machine Indicator Tester
735	A	P	Diameter, Internal, Dial bore gauge	קוטר פנימי, מד קדח גשר	[4 mm to 400 mm]	0.9 µm	Manufacturer instructions SOP 9150111	Electronic Gauge
736	A	P	Diameter, Internal, Dial bore gauge, Split Pin	קוטר פנימי, מד קדח פין מפצי	[0.5 mm up to 41.3 mm]	2.0 µm	SOP 9150110	Outside micrometer, gauge blocks
737	A	P	Length, Vernier, Dial and Digital Caliper	אורך, זחון וורניר, חוגן	Up to 2000 mm]	(8 + 5 L) μm	JIS B 7507 DIN 862 BS 887 SOP 9150105	Check master; length bars, gauge blocks L in meters BMC values stand for instruments that have resolution of 0.001 mm

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Calibr	ation –	Mecha	nnical Quantities - Length			_	כיול – גדלים מכניים - אורך
738	A	P;T	Length, , אורך, Height Gauge	Up to 1000 mm]	3 μm	JIS B 7517 BS 1643 SOP 10051	Check master; length bars, gauge blocks, indicator tester.  CMC values stand for instruments that have resolution of 0.0001 mm
739	A	P	Length, , אורך, Micrometer External מיקרומטר חיצוני	[Up to 400 mm]	(1.6+5.5L) μm	JIS B 7502 JIS B 7520	Gauge blocks, micrometer setting rods
740	A	P		[400 mm to 1000 mm]	(3+1.1L) μm	DIN 863 part 1 BS 870 SOP 10052	L in meters
741	A	P	אורד, Length, אורד, Micrometer Head	Up to 50 mm]	1.1 μm	JIS B 7504 BS 1734 DIN 863 part 2 SOP 10021	Gauge blocks, electronical gauge head L in meters
742	A	P	אורך, Length, מיקרומטר עומק Micrometer Depth	Up to 300 mm]	(2 μm +10L) μm	JIS B 7504 DIN 863 part 2 BS 1734 SOP 9150106	Gauge Blocks L in meters
743	A	P	קוטר פנימי, Diameter, Internal מיקרומטר פנימי 3 נקודות Three point internal micrometer	Up to 90 mm]	1.6 μm	DIN 863 part 4 SOP 9150129	Plain gaugeIndication 0.001 mm
744	A	P		(90 mm to 200 mm]	1.8 µm		Indication 0.01 mm
745	A	P	Length, Third Length, Inside micrometer	Up to 75 mm]	1.8 µm	DIN 863 SOP 10023	Gauge blocks, Gauge blocks accessories

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Calibr	ation –	Mecha	anical Quantities - Leng	th				כיול – גדלים מכניים - אורך
746	A	P	Diameter, Internal, Three point internal micrometer with gauge block accessories	קוטר פנימי, מיקרומטר פנימי 3 נקודות עם אביזרי מקבילונים	Up to 300 mm]	11.0 μm	SOP 9150129	
747	A	P	Length, Dial Gauge, lever	אורך, חוגן מנופי	Up to 0.8 mm]	0.8 µm	JIS B 7509 DIN 879 part 1 BS 907	Indication 0.001 mm
748	A	P			Up to 0.2 mm	1 μm	JIS B 7533 BS 2795 JIS B 7503	Indication 0.002 mm
749	A	P			(0.8 mm to 3 mm]	2.4 μm	DIN 878- DIN 2270 SOP 9150103	Indication 0.01 mm Indicator Tester
750	A	P	Length , Dial indicator	אורד, חוגן	Up to 0.05 mm	0.4 μm	JIS B 7509 DIN 879 part 1	Indication 0.005 mm
751	A	P			Up to 5 mm	0.42 μm	BS 907 JIS B 7533	Indication 0.001 mm
752	A	P			Up to 100 mm]	1 μm	BS 2795 DIN 2270	Indication 0.01 mm
753	A	P			(100 mm to 150 mm]	(0.85+5.5L) μm	DIN 878 JIS B 7503 SOP 9150107	Indicator Tester L in meters
754 755	A A	P P	Length, Indicator Tester	אורך, בודק חוגנים	Up to 25 mm Up to 5 mm	0.5 μm 0.3 μm	Manufacturer instructions SOP 9150134	Indication 0.001 mm Indication 0.0002 mm Gauge blocks

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Mecha	nical Quantities - Lengt	th				כיול – גדלים מכניים - אורך
756	A	P	Length, LVDT	אורך, מתמר אורך	Up to 50 mm	27 μm	Manufacturer instructions SOP 10022	Indicator Tester DVM
757	A	P	Length Electronic probe	אורך גשש אלקטרוני	Up to 60 mm	0.12 μm		Gauge blocks
758	A	P	Length, Height Gauge Micrometric	אורך, מד גובה מיקרומטרי	Up to 300 mm	3 μm	Manufacturer instructions SOP 9150109	Gauge blocks, electronical gauge head
759	A	P	Length, Horizontal Measuring Machine	אורך, מכונת מדידה	Up to 100 mm	0.14 μm	Manufacturer instructions SOP 10029	Indication 0.00001 mm  Measuring machine range up to 1000 mm
760	A	P			Up to 200 mm	(0.17+1.8L)μm		Indication 0.0001 mm
761	A	P	Length, Sieves	אורך, נפות אריג	Up to aperture of 4.75 mm	3 µm	ASTM – E11 ISO 3310-1 SOP 10054	Profile Projector Micrometer Head
762	A	P	P	אורך מד מרווח	Up to 1 mm	0.5 µm	JIS B 7524 DIN 2275 SOP 10055	Certo
763	A	P;T	Magnification Profile projector	הגדלה מטול אופטי	Up to 100 M	0.0092%	Manufacturer instructions JIS B 7184 SOP 10026	Optical scale M - Magnification Screen sizes up to 300 mm

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#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibra	ation –	Physic	ral Quantities - Force, To	orque	<u> </u>		ח, מומנט	כיול – ג <i>דלים פיזיקליים - כ</i> י
764	A	P	Force, Dynamometers	כוח, מדי כוח	[0.5 N to 210 N]	0.008% OR + 0.0008 N	ISO 7500-1	Comparison vs. weights
765	A	P		,,,_	(210 N to 1961 N]	0.008% OR + 0.05 N	ISO 376	Comparison vs. weights
766	A	P			(1961 N to 3130 N]	3.3 N	SOP 9015031	Comparison vs. proving
767	A	P			(3130 N to 6410 N]	4.7 N	SOP 90150318	rings and load cells
768	A	P			(6410 N to 9700 N]	7.1 N		
769	A	P			(9.7 kN to 12.9 kN]	9.5 N		
770	A	P			(12.9 kN to 17.6 kN]	13.8 N		
771	A	P			(17.6 kN to 18.8 kN]	15 N		
772	A	P			(18.8 kN to 23.1 kN]	20 N		
773	A	P;T			(23.1 kN to 26.3 kN]	22 N		
774	A	Т			(26.3 kN to 38.55 kN]	29 N		
775	A	P;T			(38.550 kN to 42.17 kN]	42 N		
776	A	P;T			(42.17 kN to 53.13 kN]	55 N		
777	A	P			(53.13 kN to 65.18 kN]	74 N		
778	A	P			(65.18 kN to 90.6 kN]	94 N		
779	A	P			(90.6 kN to 274.61 kN]	500 N		
780	A	P			(274.61 kN to 367.8 kN]	700 N		

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Physic	al Quantities - Force, Torque			ח, מומנט	יול – ג <i>דלים פיזיקליים - כ</i>
781	A	P		(367.8 kN to 450.0 kN] kN	900 N		
782	A	P		(450 kN to 4.4 MN]	11 kN		
783	A	Т	כוח, croce, Material Testing מכבשים מכבשים	(0.05 kN to 0.5 kN]	0.37 kN	Manufacturer instructions	Comparison vs. load cells
784	A	Т	Machines Presses	(0.5 kN to 1 kN]	0.79 kN	SOP 10005	
785	A	Т		(1 kN to 2 kN]	1.9 kN		
786	A	Т		(24.5 kN to 98 kN]	0.1 % OR +98 N		
787	A	Т		(98 kN to 500 kN]	0.1% OR + 1 kN		
788	A	Т		(500 kN to 4.4 MN]	(0.1% OR +15.6) kN		
789	A	P, P1	Torque, מומנט,	(0.1 N·m to 2 N·m]	0.01 N·m	ISO 6789	Torque Tester
790	A	P,P1	מפתחות מומנט Torque Wrenches	(2 N⋅m to 10 N⋅m]	0.08 N·m	SOP 10033	
791	A	P,P1		(10.0 N⋅m to 25 N⋅m]	0.17 N·m		
792	A	P,P1		(25 N⋅m to 100 N⋅m]	0.41 N·m		
793	A	P,P1		(100 N⋅m to 400 N⋅m]	1.3 N·m		
794	A	P ,P1		(400 N⋅m to 800 N⋅m]	2.1 N·m		
795	A	P, P1		(800 N·m to 1100 N·m]	2.9 N⋅m		
796	A	P	Torque, araco,	[0.1 N·m to 1 N·m]	0.0026 N·m	Manufacturer instructions	Standard weights and arms
797	A	P	orque Testers	(1 N·m to 34 N·m]	0.05 N·m	Euramet/CG-14/V.01	

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#### **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Physic	al Quantities - Force, Torque			בח, מומנט	כיול – ג <i>דלים פיזיקליים -</i> י
798	A	P		(34 N·m to 340 N·m]	0.34 N·m	SOP 90150320	
799	A	P		(340 N·m to 1062 N·m]	2.1 N·m		
800	A	P		(1062 N⋅m to 1356 N⋅m]	3.3 N·m		

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Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Physic	al Quantities - Humidity			וות	כיול – גדלים פיזיקליים - לר
801	A	P	Relative Humidity, Relative	לחות 5% rh to 10% rh at	1.2 % rh	NPL-ISBN NO.	By reference to dew point
			Humidity Gauges לחות יחסית	מדידי 10 °C to 50°C		0-904457-24-9	In HygroGen chamber
802	A	P		10% rh to 35% rh at	1.6% rh	SOP 10152	
				10 °C to 23 °C			
803	A	P		10% rh to 35% rh at	1.2 % rh		By reference to Rotronics or
				23 °C to 50°C			Comet in HygroGen chamber
804	A	P		35% rh to 50% rh at	1.6% rh		
				10 °C to 23°C			
805	A	P		35% rh to 50% rh at	1.1% rh		
				23 °C to 50°C			
806	A	T		50% rh to 60% rh at	1.6 %rh		
				10 °C to 23°C			
807	A	T		50% rh to 60% rh at	1.1% rh		
				23 °C to 50°C			
808	A	T		60% rh to 80% rh at	1.6 %rh		
				10 °C to 23 °C			
809	A	T		60% rh to 80% rh at	1.5% rh		
				23 °C to 40°C			
810	A	T		80% rh to 92% rh at	1.6 %rh		
				10 °C to 23 °C			
811	A	Т		80% rh to 92% rh at	1.5% rh		
				23 °C to 40°C			

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Physic	al Quantities - Humidity	<b>,</b>			חות	כיול – גדלים פיזיקליים - ל
812	A	P	Temperature, Relative Humidity/ Temperature Gauges	טמפרטורה רגשי לחות /טמפרטורה	5 °C to 50 °C at 5% rh to 95% rh	0.25 °C	IEC 60751 SOP 10152	By reference to Pt100 in HygroGen chamber
813 814 815	A A A	T T	Relative Humidity, Humidity Chambers, Humidity Controller	לחות יחסית, בקרים לתאי סביבה	30 % rh at 30 °C-50 °C 30% rh-50% rh 30 °C-50 °C 50% rh-90% rh 30 °C-50 °C	2.6 % rh 3.1% rh 3.6% rh	SOP 10152 SOP 9015037	Humidity Sensor Comet.  Humidity controller error is measured in one point adjacent to the controller sensor. The error does not comprise the non-uniformity in the chamber.
816 817	A A	T T	Relative Humidity, Humidity Chambers, Uniformity of Humidity.	לחות יחסית, תאי לחות, אחידות הלחות	30 % rh at 30 °C-50 °C 30% rh-50% rh	4.0 % rh 5.2% rh	SOP 10152 SOP 9015037	Uniformity of Humidity is characterized by RH values spread inside the chamber and does not comprise chamber controller errors.
818	A	Т			30 °C-50 °C 50% rh-90% rh 30 °C-50 °C	7.2% rh		

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Ins	trument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibre	ation –	Physic	al Quantities - Liquid ar	nd Air Flow		כיול – גדלים פיזיקליים – זרימה, נוזל ואוויר			
819	A	P	Flowrate Gas flowmeters	ספיקה מדי ספיקה גזיים	[0.015 L/min to 50 L/min]	0.3%	Manufacturer instructions SOP 10007	Primary standard - Cal - Trak SL800 (*)	
820	A	P, T			[0.015 L/min to 0.5 L/min]	1.1%	SOP 10047	Mass Flowmeters (*)	
821	A	P, T			(0.5 L/min to 5 L/min]	0.7%		(*) Calibration gas is N <sub>2</sub> . Volume flow rate may be	
822	A	P, T			(5 L/min to 10 L/min]	0.5%		presented in mass flow rate units at STP conditions, e.g.	
823	A	P, T			(10 L/min to 50 L/min]	1.0%		in SLPM	
824	A	P1; T1			(0.1 L/min to 0.5 L/min]	1.1%		Max pressure for calibration at P - 4.5 bar.	
825	A	P1; T1			(0.5 L/min to 5 L/min]	0.7%		Max pressure for calibration at P1 - 413 bar.	
826	A	P1; T1			(5 L/min to 10 L/min]	0.5%			
827	A	P1; T1			(10 L/min to 200 L/min]	1.0%			
828	A	P1; T1			(200 L/min to 500 L/min]	1.4%			

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Physic	al Quantities - Mass				וסה	כיול – גדלים פיזיקליים - כ
829 830 831 832 833 834 835	A A A A A A A	P P P P P P	Mass, Weights	מסה, משקולות	[1 mg to 1 g]  (1 g to 20 g]  (20 g to 50 g]  (50 g to 100 g]  (100 g to 200 g]  (200 g to 10 kg]  (10 kg to 32 kg]  (32 kg to 150 kg]	0.051 mg 0.07 mg 0.07 mg 0.043 mg 0.075 mg 0.027 g 0.66 g 11 g	ASTM-E-617 NIST Handbook 1&2-105 NIST Handbook 44 OIML IR No. R111,47,52 Manufacturer instructions SOP 90150327	"METTLER" SG 32001 "METTLER" KCC150S METTLER XP205 METTLER XP10002S
837 838 839	A A A	P;T P;T P;T		מסה, מאזניים לא או כושר הפרדה	[1 mg to 1 g] (1 g to 100 g] (100 g to 200 g]	0.013 mg 0.023 mg 0.049 mg	Euramet cg 18 Manufacturer instructions OIML 33 NIST Handbook 1-105	The uncertainty quoted will depend on the performance of the weighing instrument under calibration and will depend on the calibration uncertainty of weights used.
840 841	A A	P;T P;T	Non-automatic weigining	מסה, מאזניים לא או כושר הפרדה ז	(200 g to 8 kg] (8 kg to 10 kg]	0.014 g 0.017 g	SOP 90150319	Available weights are: OIML Class E1 from 0.001 g to 500 g
842	A	P;T	Mass Non-automatic weighing	מסה, מאזניים לא או כושר הפרדה	(10 kg to 32 kg]	0.16 g		OIML Class E2 from 500 g to 4.5 kg OIML Class F1 from 4 kg to
843	A	Т	Non-automatic weighing	מסה, מאזניים לא או כושר הפרדה	(32 kg to 150 kg]	1.2 g		135 kg NBS Handbook Class F from 50 kg to 350 kg

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# **Schedule of Accreditation**

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Calibr	ation –	Physic	cal Quantities - Mass				מסה	כיול – גדלים פיזיקליים - ו
844	A	Т	Mass Non-automatic weighing instruments Resolution 100 g	מסה, מאזניים לא אוטומטיים כושר חפרדה g 100 g	(150 kg to 500 kg]	100 g		NBS Handbook Class F from 50 kg to 350 kg NBS Handbook Class F from 50 kg to 350 kg
845	A	Т	Mass Non-automatic weighing instruments Resolution 500 g	מסה, מאזניים לא אוטומטיים כושר הפקדה 500 g	(500 kg to 2700 kg]	500 g		Test weights 5x 500 kg

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Calibr	ation –	Physic	al Quantities - Pressure	_			חץ	כיול – גדלים פיזיקליים - ל
846	A	T	Pneumatic pressure Absolute. Pressure indicating	לחץ פניאומאטי, אבסולוטי מדידי לחץ פניאומאטיים	(10 kPa to 100 kPa]	0.88 Pa/kPa	Euramet cg 17 ASTM B40.100	Comparison vs Druck 620, pressure generated by this
847	A	Т	instruments and gauges		(100 kPa to 700 kPa]	0.27 Pa/kPa	BS EN 837	nstrument
848	A	Т			(700 kPa to 68 MPa]	0.07 Pa/kPa	Manufacturer instructions SOP 90150317 SOP 10170	
849	A	Т	Pneumatic pressure	לחץ פניאומאטי, יחסי מדידי לחץ פניאומאטיים	(2 MPa to 6 MPa]	0.2 Pa/kPa	Euramet cg 17	
850	A	Т	Gauge Pressure indicating instruments and gauges	·	(6 MPa to 14 MPa]	0.13 Pa/kPa	ASTM B40.100 BS EN 837	
851	A	Т	instantens and gauges		(14 MPa to 68 MPa]	0.08 Pa/kPa	Manufacturer instructions SOP 90150314 SOP 10170	
852	A	P	Hydraulic pressure, Gauge.	לחץ הידראולי מדידי לחץ הידראוליים	(69.1 MPa to 83 MPa]	66 kPa	ASME B40.100	Comparison vs. DWT
853	A	P	Pressure indicating	מו יו י לווץ היו הואוליים	(83 MPa to 110 MPa]	84 kPa	EURAMET cg17 BS EN 837	BUDENBERG 283 A
854	A	P	instruments and gauges		(110 MPa to 138 MPa]	100 kPa	Manufacturer instruction	
855	A	P			(138 MPa to 414 MPa]	290 kPa	SOP 10006	
856	A	Т	Hydraulic pressure, Gauge.	לחץ הידראולי	(0.2 MPa to 3.6 MPa]	20 kPa	SOP 10170	Comparison vs Druck 605,
857	A	Т	Pressure indicating	מדידי לחץ	(3.6 MPa to 6.9 MPa]	42 kPa		pressure generated by this instrument
858	A	Т	instruments and gauges		(6.9 MPa to 69 MPa]	43 kPa		

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# **Schedule of Accreditation**

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Calibra	ation –	Physic	al Quantities - Tempera	ture			טמפרטורה 	כיול – גדלים פיזיקליים <del>-</del> י
859	A	P	Temperature. Resistance	טמפרטורה	[-80 °C to -40 °C]	0.06 °C	IEC 60751	SPRT
860	A	P	Thermometers	מדי חום התנגדות	[-40 °C to -10 °C]	0.04 °C		Pt 100
861	A	P			[-10 °C to 50 °C]	0.03 °C	SOP 10003	
862	A	P			0.01 °C (Triple point of water)	0.01 °C		
863	A	P			25 °C	0.015 °C		
864	A	P			[50 °C to 100 °C]	0.014 °C		
865	A	P			[100 °C to 150 °C]	0.05 °C		
866	A	P			[150 °C to 250 °C]	0.06 °C		
867	A	P			(250 °C to 420 °C]	0.13 °C		
868	A	P			(420 °C to 620 °C]	0.5 °C		
869	A	P	Temperature.	טמפרטורה	[-80 °C to -40 °C)	0.4 °C	ASTM E77	Pt 100
870	A	P	Liquid in Glass Thermometers	מדי חום, נוזל בזכוכית	[-40 °C to 100 °C)	0.13°C	SOP 9015039	
871	A	P			0 °C	0.03 °C		
872	A	P			25 °C	0.05 °C		
873	A	P			(100 °C to 200 °C]	0.2 °C		

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# **Schedule of Accreditation**

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibr	ation –	Physic	al Quantities - Temperature			ומפרטורה	כיול – גדלים פיזיקליים - י
874	A	P		(200 °C to 400 °C]	0.45 °C		
875	A	P		(400 °C to 450 °C]	0.7 °C		
876	A	P	Temperature. Thermocouples, Noble	0 °C (Ice point)	1.0 °C	ASTM-E-220 ASTM-E-230	Pt 100 At ice point
877	Α	P	Metal (S, R,)	[100 °C to 400 °C] 0.8 °C	0.8 °C	Euramet cg8	thermocouples in oil baths
878	A	P	(3,5,11)	(400 °C to 600 °C]	0.9 °C	SOP 9015038	and fluidized bath vs. Pt.100
879	A	P		(600 °C to 1000 °C]	1.7 °C		
880	A	P	Temperature. Thermocouples Type B  B אמדים תרמיים מסוג B	100 °C to 1000 °C	1.7 °C	ASTM-E-220 ASTM-E-230 Euramet cg8 SOP 9015038	
881	A	P	Temperature.  Base Thermocouples  T, K, N, א מספרטורה T, K, N, א מספרטורה E, J	0 °C (Ice point)	0.4 °C	ASTM-E-220 ASTM-E-230	Measurements by means of Pt 100 in oil baths and fluidized bath.
882	Α	P	T, K, N, E, J	[-80 °C to 250 °C]	0.2 °C	Euramet cg8	Measurements by means of
883	A	P		[250 °C to 300 °C]	0.3 °C	SOP 9015039	thermocouple type S in furnace
884	A	P		[300 °C to 620 °C]	0.6°C		
885	A	P		(620 °C to 1000 °C]	2 °C		
886	A	Т	Temperature, טמפרטורה Resistance Thermometers גששי טמפרטורה התנגדות	[-25 °C to 140 °C]	0.4 °C	IEC 60751 SOP 9015039	Dry blocks calibrators Hart Scientific 9105 Pt 100, resistance meter Isotech bridge

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests: Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.

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Calibr	ation –	Physic	al Quantities - Tempera	ture			טמפרטורה	כיול – גדלים פיזיקליים - י
887	A	Т			(140 °C to 600 °C]	0.5 °C		Isotech Jupiter 852 Site, Pt. 100 , Isotech bridge S type th/c , Hydra
888	A	Т	Temperature, Base thermocouples	טמפרטורה צמדים תרמיים בסיסיים	[-25 °C to 600 °C]	1.7 °C	ASTM-E-220 ASTM-E-230 SOP 9015039	Dry blocks calibrators Hart Scientific 9105 Isotech Jupiter 852 Site Pt 100, resistance meter Isotech bridge S type th/c, Hydra
889 890	A	Т	Temperature, Bimetal thermometers	טמפרטורה גששי טמפרטורה דו-מתכתיים	[-25 °C to 140 °C] (140 °C to 600 °C]	1.6 °C 2.8°C	ASTM-E-220 ASTM-E-230 IEC 751 SOP 9015039	Dry blocks calibrators Hart Scientific 9105 Pt 100, resistance meter Isotech bridge Isotech Jupiter 852 Site, Pt. 100, Isotech bridge
891	A	P:T	Temperature, Temperature indicators and simulators for Resistance sensors	טמפרטורה, מדי ומדמי טמפרטורה עבור מדי התנגדות	-200 °C to 850 °C	0.01 °C	EURAMET cg-11 SOP 10752 SOP 10756	Calibration by means of electrical calibration,
892	A	P:T	Temperature, Temperature indicators and simulators for Base metal thermocouples	טמפרטורה, מדי ומדמי טמפרטורה עבור צמדים תרמיים מתכות בסיסיות	-200 °C to 1370 °C	0.12 °C	EURAMET cg-11 SOP 10750 SOP 10758	Calibration by means of electrical calibration, cold junction compensation on
893	A	P:T	Temperature, Temperature indicators and simulators for Noble metal thermocouples	טמפרטורה, מדי ומדמי טמפרטורה עבור צמדים תרמיים מתכות אצילות	0 °C to 1760 °C	0.4 °C	EURAMET cg-11 SOP 10750 SOP 10758	Calibration by means of electrical calibration, cold junction compensation on

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

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Calibr	ation –	Physical Quantities - Temperature				כיול – גדלים פיזיקליים - טמפרטורה		
894	A	P, T	Temperature, Temperature indicators and simulators for Base metal thermocouples	טמפרטורה, מדי ומדמי טמפרטורה עבור צמדים תרמיים מתכות בסיסיות	-200 °C to 1370 °C	0.1 °C	EURAMET cg-11 SOP 10750 SOP 10758 SOP 10754	Calibration by means of electrical calibration, cold junction compensation off
895 896 897 898	A A A	P, T P, T P, T P, T	Temperature, Temperature indicators and simulators for Noble metal thermocouples	טמפרטורה, מדי ומדמי טמפרטורה עבור צמדים תרמיים מתכות אצילות	0°C 100 °C 200 °C 200 °C to 1760 °C	0.17 °C 0.13 °C 0.11 °C 0.1 °C	EURAMET cg-11 SOP 10750 SOP 10758 SOP 10754	Calibration by means of electrical calibration, cold junction compensation off
899 900 901 902 903 904	A A A A	P,T P,T P,T P,T P,T P,T	Temperature, Furnaces Controller	טמפרטורה, בקרים לתנורים	[-70 °C to -40 °C] [-40 °C to 70 °C] [70 °C to 180 °C] (180 °C to 250 °C] (250 °C to 700 °C] (700 °C to 1000 °C]	0.4 °C 0.7 °C 0.5 °C 1.1 °C 2.1 °C 2.5 °C	MIL-STD-810-F AMS 2750E SAE-AMS-H-6088 MIL-H-6875 SOP 9015037	Thermocouples
905 906 907 908	A A A	P,T P,T P,T P,T	Temperature, Furnaces Controller Including Uniformity	בקרת תנורים כולל אחידות	[-70 °C to 180 °C] (180 °C to 250 °C] (250 °C to 700 °C] (700 °C to 1000 °C]	0.7 °C 1.1 °C 1.4 °C 3.6 °C	MIL-STD-810-F AMS 2750E SAE-AMS-H-6088 MIL-H-6875 SOP 9015037	Thermocouples

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